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THESIS

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AN ADVANCED STUDY OF NATURAL CONVECTION
IMMERSION COOLING OF A 3 x 3 ARRAY OF
SIMULATED COMPONENTS IN AN ENCLOSURE
FILLED WITH DIELECTRIC LIQUID

by

Terry J. Benedict

June 1988

Co-advisors:

Matthew D. Kelleher
Yogendra Joshi

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An Advanced Study of
Natural Convection Immersion Cooling
of a 3 x 3 Array of Simulated Components
in an Enclosure Filled with Dielectric Liquid

by

Terry J. Benedict
Lieutenant, United States Navy
B.S., United States Naval Academy, 1982

Submitted in partial fulfillment of the
requirements for the degree of

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ABSTRACT

An experimental study has been conducted to examine the three-dimensional natural convection heat transfer from an array of simulated electronic components immersed in a chamber filled with Fluorinert FC-75, a commercially available dielectric liquid. The top and bottom walls of the chamber were maintained at uniform temperature while all other surfaces were insulated. The simulated components were in the form of a 3 x 3 array of discrete protruding aluminum blocks, each with geometrical dimensions of a 20 Pin Dual-inline-Package. The components were electrically powered resulting in a range of energy dissipation levels from 0.1 to 3.1 watts. Flow visualization in steady state was accomplished using Magnesium particles illuminated by a Helium Neon laser plane. Component surface temperature measurements allowed determination of the heat transfer characteristics. Timewise fluctuations of temperature at several locations were measured with increasing power levels.

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NOMENCLATURE

SYMBOL	DESCRIPTION	UNITS
A	Area	m ²
α	Thermal Diffusivity	m ² /sec
β	Thermal Expansion Coefficient	1/K
c _p	Specific Heat	J/kg-°C
δ	Uncertainty in the Variables	Various
g	Acceleration of Gravity	m/sec ²
Gr	Grashof Number	Dimensionless
h	Heat Transfer Coefficient	W/m ² -°C
k	Thermal Conductivity	W/m-°C
L	Characteristic Length	m
Nu	Nusselt Number	Dimensionless
Nu _C	Nusselt Number at the Center	Dimensionless
ν	Kinematic Viscosity	m ² /sec
Pr	Prandtl Number	Dimensionless
Q _{con}	Energy Loss by Conduction	W
Q _{conv}	Energy Added to the Fluid	W
Q _{in}	Energy Input to the Heaters	W
R	Resistance of the Precision Resistor	ohms
R _{con}	Total Thermal Resistance	°C/W
R _{at}	Temperature Based Rayleigh Number	Dimensionless
R _{af}	Flux Based Rayleigh Number	Dimensionless

ρ	Density	kg/m^3
T_b	Back Surface Temperature of Board	$^\circ\text{C}$
T_c	Average Heat Exchanger Temperature	$^\circ\text{C}$
T_f	Average Film Temperature	$^\circ\text{C}$
T_s	Back Surface Temperature of the Component	$^\circ\text{C}$
V_{in}	Input Voltage	Volts
V_h	Voltage Across the Heaters	Volts

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I. INTRODUCTION

A. STATEMENT OF PROBLEM

As microelectronic components continue to decrease in size and increase in component density, the problem of heat dissipation becomes increasingly more critical in the design of circuits and components. A five-order-of-magnitude increase in circuit integration in the last 25 years has been associated with successive revolutions in components technology.

With the recent development of CMOS, industry has seen an almost three-order-of-magnitude reduction in size, an order-of-magnitude increase in the characteristic component dimensions and perhaps, most importantly, a precipitous drop in transition switching energy from 10^{-9} J in 1960 to nearly 10^{-13} J in present day devices. It is anticipated that power dissipation of 100 W in a 10 million component chip could be encountered by 1990. This would result in component heat fluxes in excess of 100 W/cm^2 [Bar-Cohen, 1987, pp. 159-175]. The strong requirement to keep components at low temperature levels, 100°C to 125°C , does exist, since for every 20°C decrease in components temperature, the components failure rates are cut in half [Oktay, 1986, pp. 36-42].

B. BACKGROUND

Air cooling is the standard design in today's systems. Advances in air cooling technology now include impingement cooling and combined conduction and air cooling technology which offers even higher cooling rates than natural or forced convection air cooling. However, air as a heat transfer medium is extremely limited not only in its ability to transfer heat but also in its capacity to carry the transferred energy with a reasonable temperature increase [Baker, 1972, pp. 213-222].

Special component surfaces have been investigated. Features such as Turbulence Promoting Fins (TPF) have significantly higher cooling enhancements when used with special gases such as Helium as the closed cycle coolant [Kishimoto et al., 1983, pp. 286-93]. By doing so, a 300% greater dissipation rate can be reached than in an open cycle with air as the coolant.

Forced convection in liquids offers greater heat transfer coefficients than does natural convection in liquids or air. However, forced convection introduces two major problems: (i) greater amounts of expensive coolant are required and (ii) pumps and external plumbing increase the size and reduce the reliability by introducing the possibility of vibration related failures to the system [Baker, 1973, pp. 163-173].

Boiling can produce very large scale heat transfer coefficients, but it also introduces major problems: (i) boiling restricts the physical design of the system, (ii) if the surface is very smooth, as most electronic components are, a high degree of superheat may be required so that nucleation can occur. The occurrence of periodic boiling due to the high local heat flux may result in severe local turbulence and mechanical damage and (iii) boiling may result in the concentration of impurities at the nucleation site [Baker, 1973, pp. 163-173].

C. STUDIES ON NATURAL CONVECTION COOLING OF ELECTRONIC DEVICES

1. Numerical Studies

Of the different heat transfer modes mentioned above, immersion cooling by natural convection offers not only high heat transfer potential, but also a practical means of controlling circuit temperatures. However, only limited heat transfer data are available for immersion cooling of discrete, protruding heat sources [Liu et al., 1987, pp. 309-30]. Early studies of natural convection heat transfer were motivated by applications such as energy conservation and solar energy collection. The pertinent length scales were several order of magnitude higher than those applicable in cooling of electronic equipment. However, recent studies have focused on computational and

experimental studies of natural convection cooling in electronic components.

[Han et al., 1984, pp. 21-28] have used numerical simulation to investigate the transient laminar natural convection in a rectangular enclosure with a localized constant heat flux source. [Acharya et al., 1983, pp. 855-66] have investigated the natural convection phenomenon in an inclined square box shaped enclosure which has energy sources in it. [Jaluria, 1985, pp. 883-92] investigated the interacting natural convection flows generated by flush, isolated thermal energy sources, such as electronic components, located on a vertical adiabatic surface. [Jaluria, 1982, pp. 223-27] also analytically studied the natural convection flow due to multiple isolated heated elements located on a vertical surface. [Torok, 1984, pp. 49-57] used the finite element technique to predict component and board temperatures and heat fluxes.

[Kuhn et al., 1986, pp. 55-62] have investigated the transient three-dimensional natural convective flow and heat transfer within a rectangular box following a sudden temperature change on a rectangular portion of one vertical wall. They found that when two elements are symmetrically placed on the wall, the distance between them has only a slight effect on the mean heat transfer distribution. However, it does have a significant effect on the local Nusselt number. [Shakerin et al., 1986, pp. 17-22]

investigated the natural convection flow adjacent to a heated wall with single and repeated, two-dimensional, rectangular roughness elements. [Oosthuizen et al., 1987, pp. 1-7] studied the heat transfer rates from an element of square cross-sectional shape held at a uniform temperature and mounted on a vertical adiabatic wall of a tilted square enclosure. They found that the mean heat transfer rate from the block did not vary continuously with the angle of inclination.

[Liu et al., 1987, pp. 486-97] have conducted a finite difference numerical study of natural convection flow in a rectangular enclosure of an array of simulated components that are mounted on a vertical wall. The results of this numerical study have been presented for enclosure widths of 18 and 30 mm. It was concluded that:

- The temperature field in the enclosure is characterized by boundary layer regions surrounding individual components.
- There are only small interferences among the components, especially for the lower rows.
- The maximum temperatures on the components surfaces are located on the upper horizontal surfaces of the components. Lower temperatures have been found on the lower horizontal faces of the components in the bottom row.
- The results for the 30 mm width are essentially the same as those for the 18 mm, indicating only a minor dependence on the enclosure width.

[Liu et al., 1987, pp. 309-30] have also observed a local oscillatory surface temperature response in the same

enclosure. Their study found that the components surface temperatures have a tendency to fluctuate within a range of approximately 3°C with a period of 4 seconds.

2. Experimental Studies

Numerous experimental studies have been conducted concurrently with the numerical studies described above. Two of the earliest studies were conducted by [Baker, 1972, pp. 213-22] and [Baker, 1973, pp. 163-73]. The purpose of these investigations was to examine liquid immersion techniques for cooling miniature heat sources, specifically effects of component size on the convective heat transfer. [Goel et al., 1986, pp. 1341-46] experimentally investigated the two-dimensional natural convection flow from a long, finite size heat source located on a vertical or inclined plate in air. The principal items of interest were the nonboundary layer effects that arise in the flow, particularly in the vicinity of the source. Flow separation was observed at large inclinations.

[Milanez et al., 1986, pp. 1347-52] experimentally studied the interaction of two horizontal, wide strips on a vertical adiabatic wall in both air and water. They found the results of their experiment in good agreement with past numerical studies. [Ortega et al., 1986, pp. 5-15] presented the results for a series of experiments in air designed to measure the natural convective heat transfer rates and the thermal characteristics of a rectangular array

of cubical roughness elements mounted on an insulated plane wall, with and without a shrouding wall. [Parks et al., 1987, pp. 91-109] simulated microelectronic circuits with thin foil heaters for both flush and protruding components. They found that the protruding heaters have approximately 15% higher coefficients and that the upper heaters have varying coefficients depending upon the array configuration.

A number of studies have been conducted at the Naval Postgraduate school. [Knock, 1983] studied the effect of the location of a single protruding heater in an enclosure filled with water. [Pamuk, 1987] investigated the heat transfer characteristics of an array of nine protruding components immersed in a dielectric fluid in an uninsulated chamber. [Hazard, 1987] studied the natural convection liquid cooling of a vertically arranged components array with and without a shrouding wall.

D. OBJECTIVES

This experimental work was motivated by the numerical study of [Liu et al., 1987, pp. 486-97] and the recent experimental studies of [Pamuk, 1987]. The objectives for this thesis are:

- To design and build a circuit card of nine simulated components and determine the rate of heat transfer for various power inputs.
- To determine the natural convection flow patterns developed in the chamber by means of flow visualization.
- To correlate the data in terms of dimensionless heat transfer parameters such as Rayleigh vs. Nusselt number.

II. EXPERIMENTAL APPARATUS

A. GENERAL CONSIDERATIONS

This experimental study is a continuation of past experiments conducted at the Naval Postgraduate School [Knock, 1983; Pamuk, 1987; Hazard, 1987]. The purpose of this work was to examine natural convection heat transfer and fluid flow from a 3×3 element array of simulated electronic components. A major change from the previous experiments was the design of the simulated circuit card. In [Pamuk, 1987] an arrangement of vertical components was used. The present study utilized a horizontal arrangement. A decision to increase the card thickness was made to reduce the contamination of the dielectric fluid by the loose insulating material previously used and also to reduce the conduction loss through the card.

The experimental apparatus consists of a chamber filled with a dielectric fluid. Top view of the chamber is provided in Figure 2.1. The top and bottom surfaces of the chamber are maintained at a prescribed temperature by means of two heat exchangers and two separate chilled water circulation baths. One vertical wall of the chamber simulates a circuit card. It contains nine simulated components in a 3×3 array, while all other vertical walls are insulated. The geometrical arrangement of the simulated

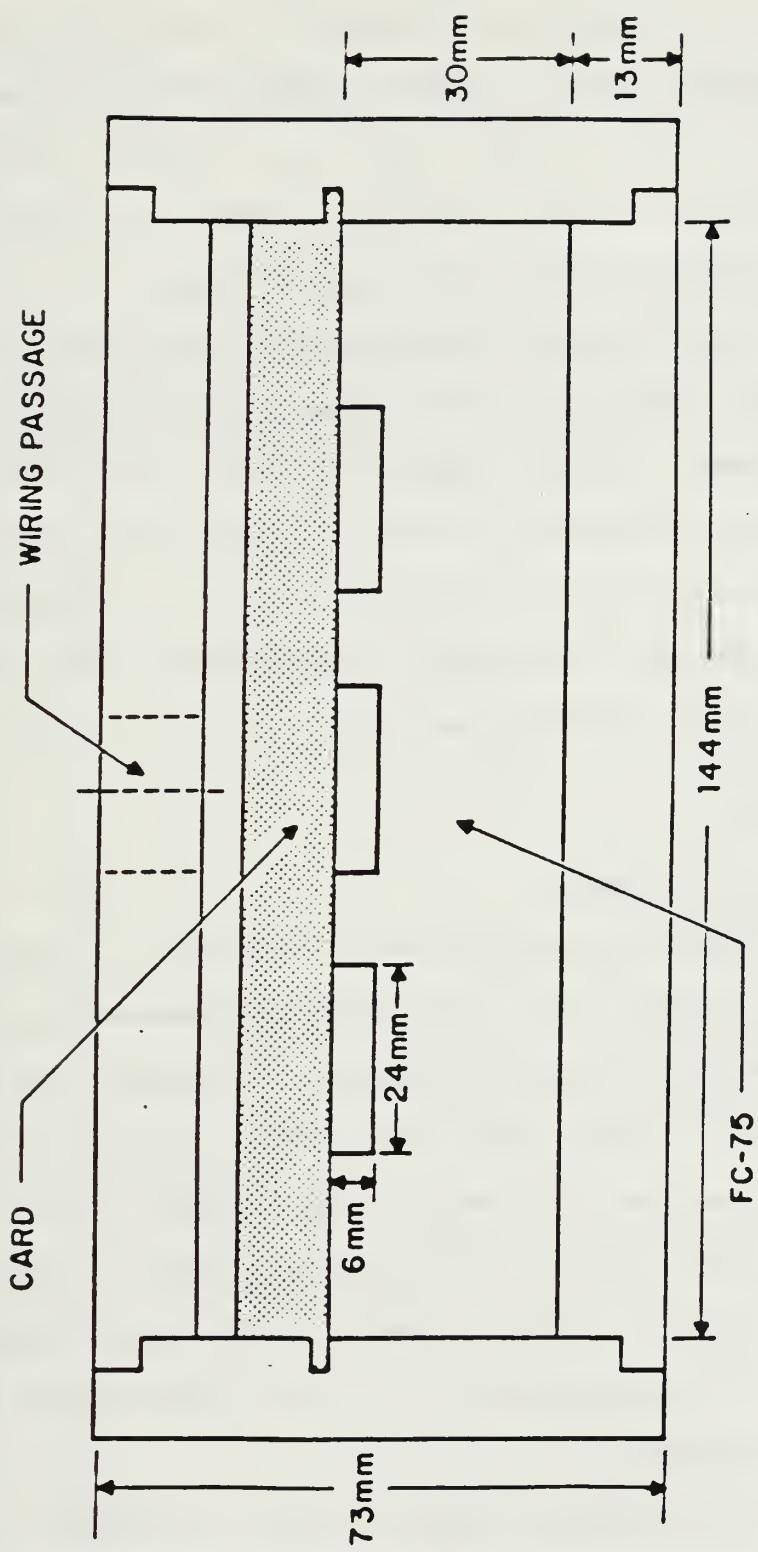


Figure 2.1 Top View of Chamber

components on the card is seen in Figure 2.2. The components were chosen to simulate an array of 20 pin Dual-in-line-packages (DIPS). Their dimensions are identical to those used by [Liu et al., 1987, pp. 486-97; Liu et al., 1987, pp. 309-30; Pamuk, 1987] in order to permit future comparisons of experiments and computations.

The heating elements were made of aluminum and heated by means of small foil type resistance heaters attached to the bottom surfaces. The temperatures of the faces of the elements were measured by means of embedded thermocouples. Data were recorded and processed using an automatic data acquisition system. The major components of the system are described in the following section.

B. COMPONENTS

1. Heating Element

Each heating element was a block of aluminum 6mm by 8mm by 24mm (Figure 2.3). The temperatures at the faces of the blocks were measured by means of thermocouples placed within grooves (0.5mm deep) on each surface. The front surface thermocouple was passed through the block by means of a 1.02mm hole drilled through the block. All grooves were filled with high thermal conductivity epoxy and smoothed prior to attachment to the simulated circuit card.

2. Thermocouples

All thermocouples were 10-mil (0.254mm) copper-constantan. These small wires were chosen to minimize the

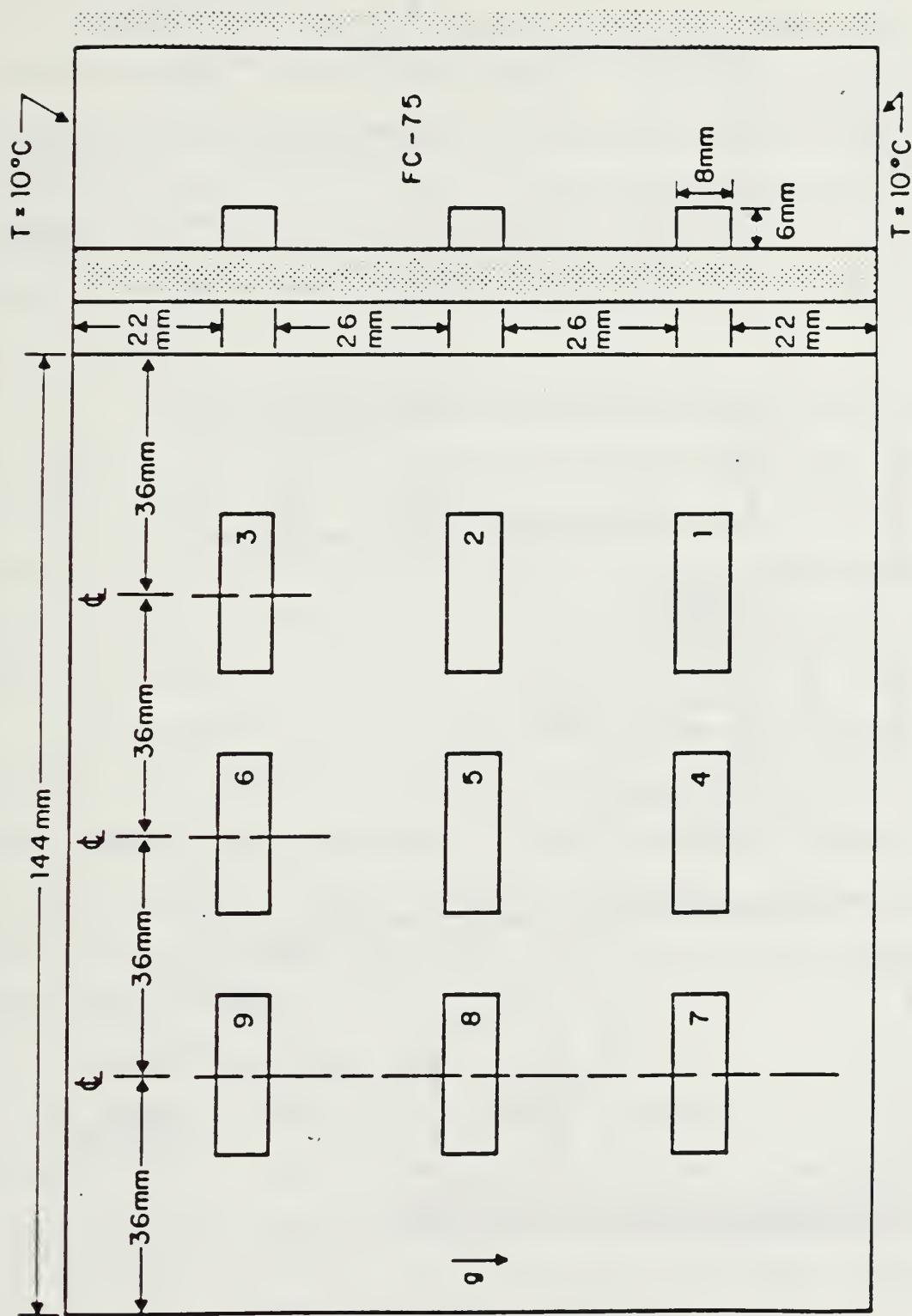


Figure 2.2 Simulated Circuit Card

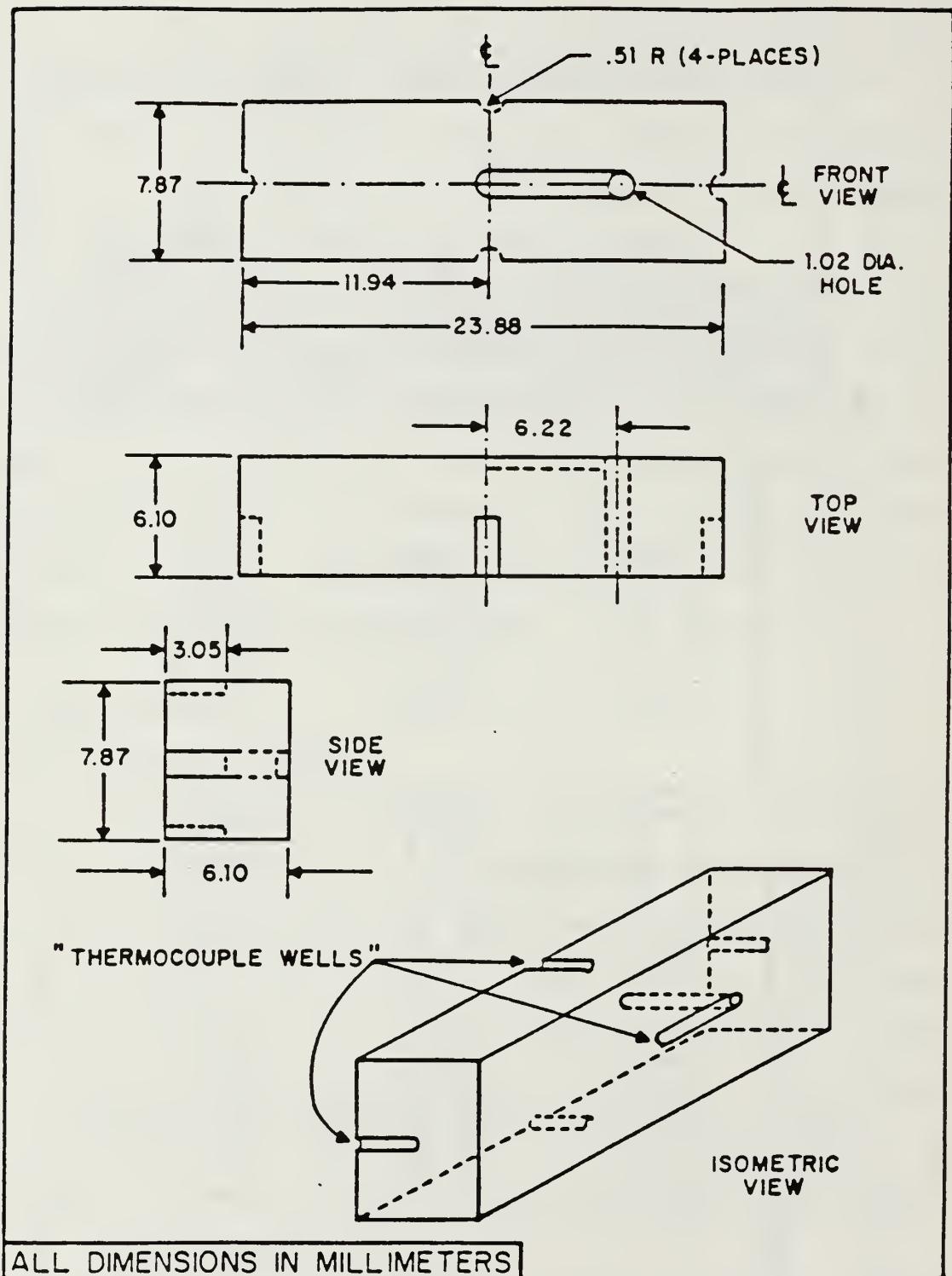


Figure 2.3 Heating Element

material removed from the block. The thermocouples were manufactured by using an arc welder designed for such purposes. The setting for both current time and gas pressure (argon) was kept at 'medium.' Due to the extremely small diameter of the wire the gas pressure was carefully regulated to less than 5 psig. The thermocouples were also checked for continuity due to the fact that the arc welder tended to embrittle the copper wire at the bead.

3. Heaters

A nearly constant heat flux condition was maintained at the base of the block by use of thin (0.18mm) foil type heaters (Figure 2.4). Each of the heaters was measured to have a resistance between 10.5 and 10.6 ohms. These heaters were designed to align with the blocks. Holes were provided within the heaters to pass the various thermocouple wires.

The power leads of the heaters were gold plated to ensure a low electrical contact resistance. Wires from the power supply were attached to the leads by means of soldering. After ensuring proper alignment, the heaters were bonded to the blocks by means of a high thermal conductivity epoxy.

4. Simulated Circuit Card

Three grooves of 0.5mm depth were made on the front of the card in order to allow the heaters to be mounted below the surface and thus prevent the dielectric fluid from seeping under the blocks and introducing a variable, unknown

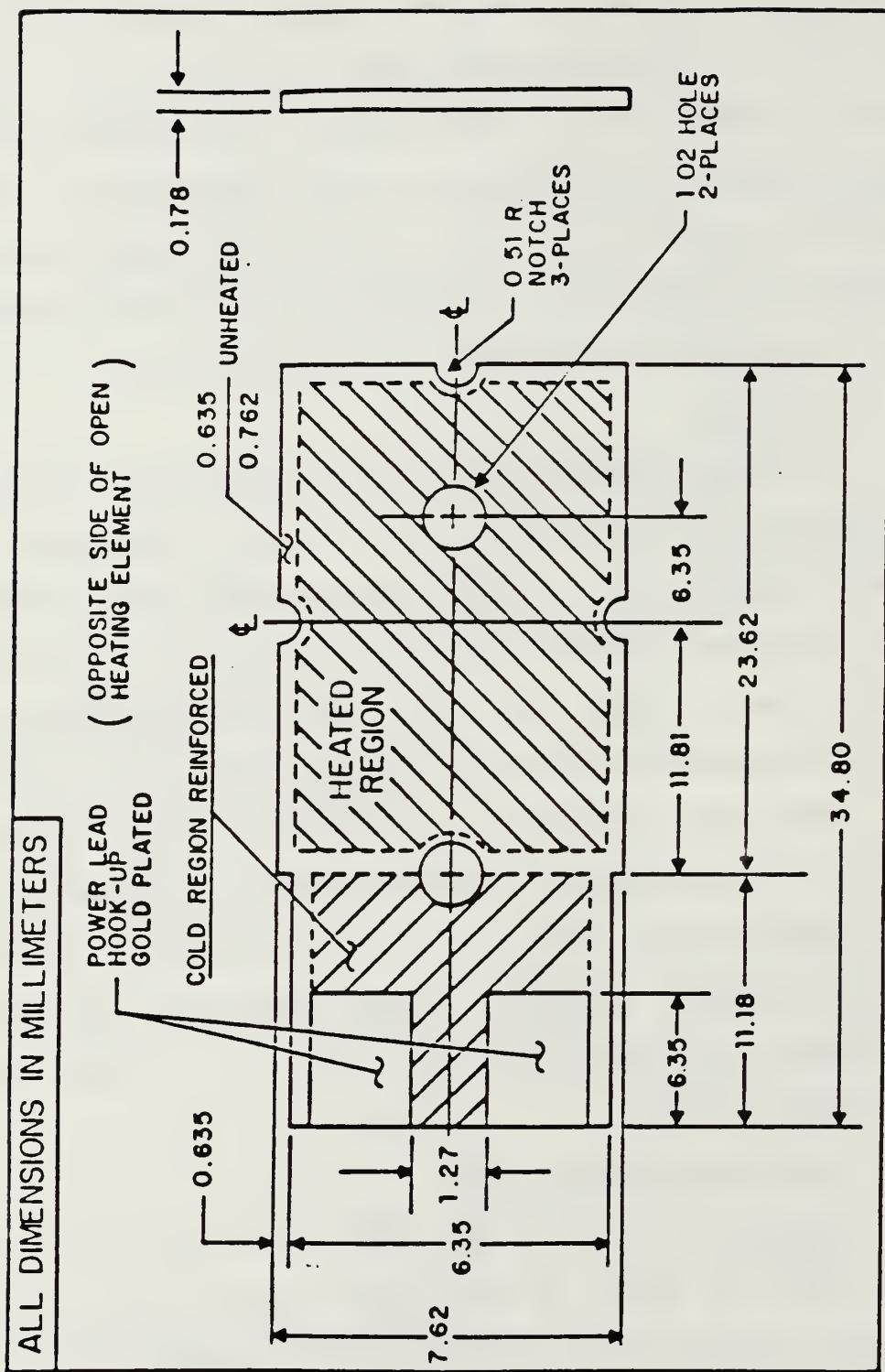


Figure 2.4 Foil Type Heaters

resistance. The heating elements were bonded to the circuit card with a low thermal conductivity epoxy.

5. Test Chamber

The test chamber was constructed of plexiglass (13mm thick) and had inside dimensions of 120mm in height, 144mm in length, and 30mm in width. The wires were fed through the grooves in the back of the circuit card to a "Tygon" tube on the back wall. The chamber also contained two small pressure equalization outlets, located at the top and the bottom of the front vertical surface.

6. Heat Exchangers

The two aluminum heat exchangers measure 38mm by 65mm by 274mm. The details of the heat exchangers are available in [Knock, 1983]. Aluminum plates 3mm thick were used as top and bottom surfaces. These plates were grooved 2.5mm to provide slots for the thermocouples. This left a 0.5mm wall thickness of aluminum between the thermocouple bead and the surface in contact with the dielectric fluid. The resulting conductive thermal resistance was found to be negligible. The heat exchangers were each attached to individual coolant baths by means of "Tygon" tubing. Four 10 mil (0.254mm) thermocouples, two on the top and two on the bottom, were used to read the heat exchanger temperatures.

7. Flow Visualization

Visualization was accomplished with magnesium powder, 325 mesh. Magnesium has a density of 1.92 g/cm^3 compared to 1.76 g/cm^3 for FC-75, resulting in a large suspension time of the particles. The beams from the light sources were spread into plane sheets which illuminated the particles suspended in the FC-75. This technique allowed for the visualization of a single plane of the flow field. Other planes were examined by the realignment of the apparatus. A four milli-watt helium neon laser and a cylindrical lens were used for the time lapse camera photos (Figure 2.5).

8. Assembly

After sliding the card into the slot in the chamber, both the thermocouple and power wires were run out through the 1.27cm diameter extension pipe on the back of the chamber to the connected "Tygon" tubing of approximately 1.0 meter in length.

Rubber o-rings were placed in grooves located on the top and bottom surfaces of the chamber and the thin aluminum plates were set in place. The heat exchangers were then set on the plates and clamped by means of specially made aluminum clamps to ensure a proper seal. The inlet and outlet tygon tubes were attached to the constant temperature baths for each heat exchanger. Finally, the pressure

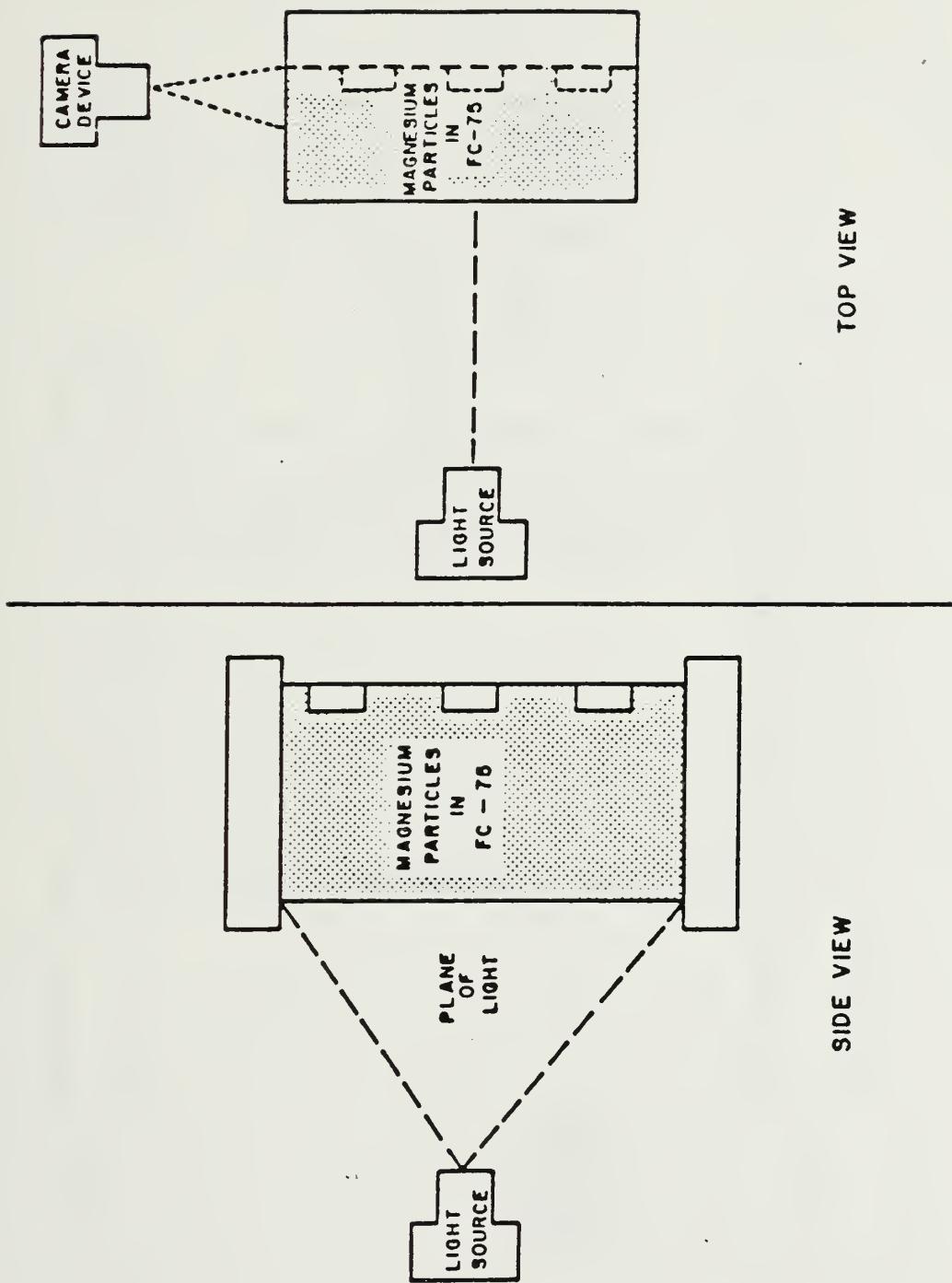


Figure 2.5 Flow Visualization Set-Up

equalization tubes were attached to the chamber. A schematic of the entire assembly is shown in Figure 2.6.

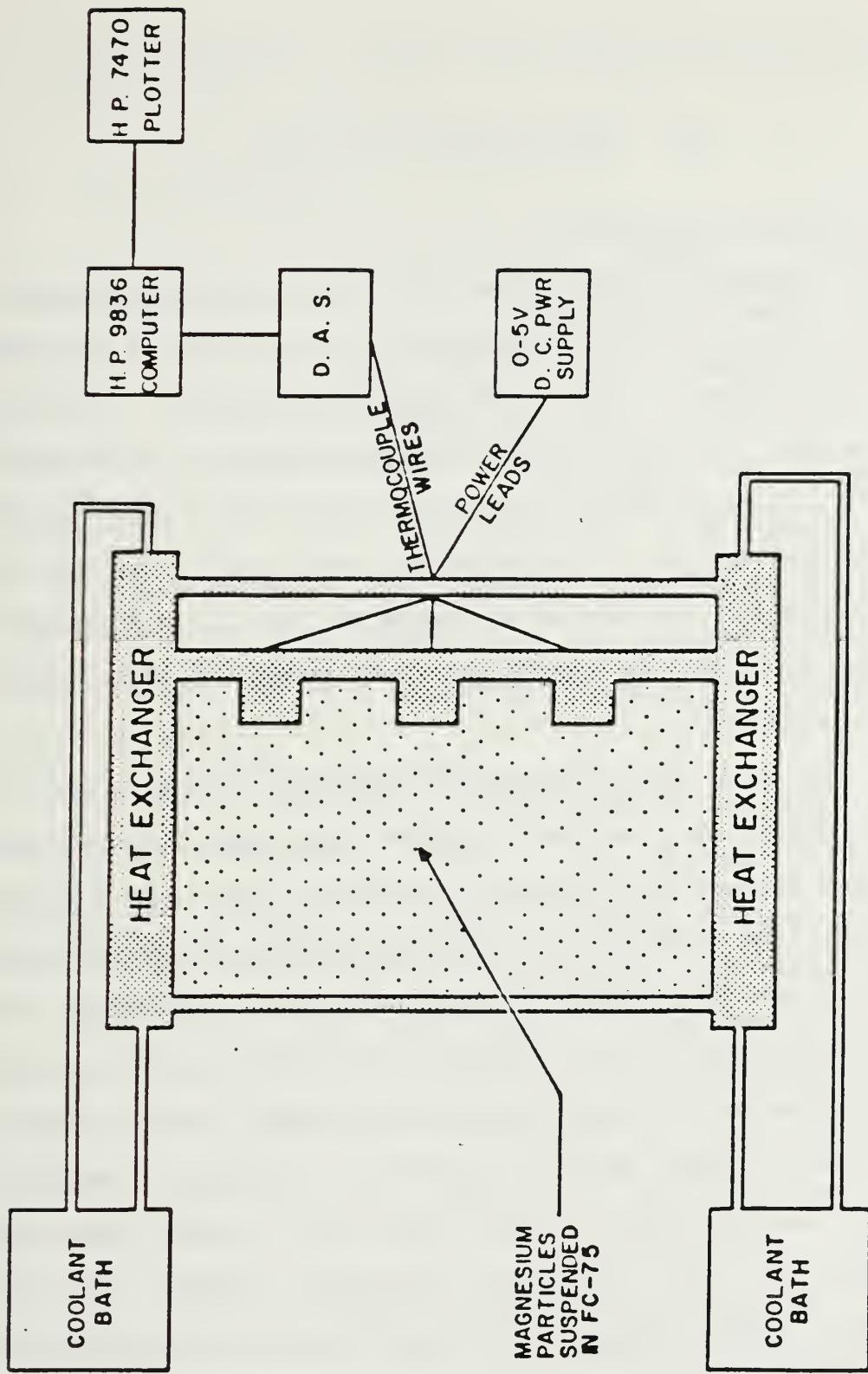


Figure 2.6 Schematic of Entire Assembly

III. EXPERIMENTAL PROCEDURE

A. APPARATUS PREPARATION

After assembling the apparatus, the chamber was filled with the dielectric fluid through the top vent tube by means of a small funnel and a hypodermic syringe. To damp disturbances, the entire apparatus was placed on a separate platform. This platform also served as a means of leveling the chamber by use of adjustable screw legs. Since the entire apparatus was sealed by means of four clamps it could be tilted in order to remove the last remaining air bubbles inside the chamber.

The use of a single constant temperature bath providing cooling water in series to the top and bottom heat exchangers proved inefficient to maintain both the top and the bottom heat exchangers at the same constant temperature. A second bath was added so that each heat exchanger was supplied individually and could be adjusted separately. The ten terminals on the power supply panel were used to supply power to the heaters on the simulated components. The first terminal was the main input, the next nine were the terminals to the individual heaters located on each component. These heaters were connected in series with the 2 ohm precision resistors. This arrangement was repeated

for each component. These nine units were then connected in parallel to the main input.

B. DATA ACQUISITION

Prior to energizing the power supply or the constant temperature baths all the thermocouples were scanned to measure the starting steady state temperatures. The constant temperature baths were set at 10°C by means of adjustment dials located on the baths. Throughout each experiment the bath supplying the top heat exchanger required constant monitoring. As the power levels increased, the bath temperature was reduced accordingly to maintain the top heat exchanger thermocouple readings at a constant 10°C.

The desired voltage was obtained by setting the power supply to the desired level. The reading on the power supply was verified by means of reading channel number 61, the main power input channel, on the data acquisition panel.

Approximately four hours were allotted for the system to achieve steady state. For this experiment, the steady state condition was defined as a majority of the thermocouple readings changing less than 0.2°C during three separate readings taken at ten minute intervals. The bath temperatures were checked to ensure they were at 10°C. If they were in agreement then the data was recorded by means of the program "ACQUIRE" (Appendix C). This program scanned all 76 channels and converted the emf signals from the

thermocouples to temperatures in degrees Celsius. The power to the heater was determined by utilizing the precision 2 ohm resistor. This resistor was connected in series with the heater and allowed the measurement of the current through this configuration. This current was then multiplied by the measured voltage of the heater to produce the power input to the component.

A second program "Fastscan" (Appendix C) was developed to scan three individual channels. Each of the three channels, numbers 1, 13, 32, was scanned individually at a rate of 3 scans per second for a period of 200 seconds. The main intention in doing so was to isolate any periodic behavior caused by the flow past these three thermocouples. A third program "Plot" (Appendix C) was developed to plot these results on a HP model 7470A plotter.

Flow visualization was conducted by means of 325 mesh Magnesium particles and a four milliwatt laser focused with a cylindrical lens. The magnesium particles were injected into the chamber by way of the bottom vent tube. A motor driven Nikon F3 camera with a Micro-Nikkor 55mm lens and a Nikon MT-2 Intervalometer was used for the long-time photography. The time exposure photographs of length 8 or 20 seconds were taken at the various power levels where heat transfer data had been obtained. The photographs were taken of the three columns of components by placing the camera at a ninety degree angle to the plane created by the laser.

This configuration was then reversed to obtain photographs of three separate planes in the chamber.

C. DATA ANALYSIS

1. Determination of the Nusselt Number

The Nusselt Number is defined as the following:

$$Nu = \frac{hL}{k_f} \quad (3.1)$$

where L is a characteristic length, taken here as the length of the component in the vertical direction, k_f is the thermal conductivity of the fluid, and h is the convective heat transfer coefficient. All fluid properties were taken to be a function of the average film temperature.

To evaluate the heat loss, one thermocouple was placed directly behind each of the heated blocks. A series of nine thermocouples were also attached to the back of the card. These temperatures were used to calculate the conduction loss through the back of the card.

One dimensional conduction resistance, R_{con} , for the simulated board was determined from:

$$R_{con} = \frac{L}{kA} \quad (3.2)$$

where L is the length along the conduction path i.e., the thickness of the board, k is the thermal conductivity of the material (Appendix A) and A is the area normal to the

conduction path. The area normal to the path of conduction was calculated as the area directly behind the components back, 192mm^2 . By doing so spreading losses were neglected. The conduction loss is then:

$$Q_{\text{con}} = \frac{T_s - T_b}{R_{\text{con}}} \quad (3.3)$$

Power input to each component is calculated from:

$$Q_{\text{in}} = \frac{(V_{\text{in}} - V_h)V_h}{R} \quad (3.4)$$

where V_{in} is the input voltage applied to both the 2 ohm resistor and the heater which is in series with it. V_h is the voltage drop across the heater. The difference between V_{in} and V_h gives the voltage drop across the 2 ohm resistor.

The net energy added to the fluid in the chamber is the difference between Q_{in} and Q_{con} which by Newton's Law of cooling is:

$$\begin{aligned} Q_{\text{conv}} &= Q_{\text{net}} = hA(T_{\text{avg}} - T_c) \\ &= Q_{\text{in}} - Q_{\text{con}} \end{aligned} \quad (3.5)$$

where,

A = The total wetted surface area of the components,

T_{avg} = Area weighted average surface temperature,

calculated by,

$$T_{avg} = \frac{\sum A_i T_i}{\sum A_i} \quad (3.6)$$

where,

T_i = Temperature of the i^{th} surface of the components,

A_i = Area of the i^{th} surface of the components.
The summation of the index i varies from 1 to 5,

and,

T_C = Average heat exchanger temperature.

Thus,

$$h = \frac{Q_{conv}}{A_{tot} (T_{avg} - T_C)} \quad (3.6)$$

The above procedure was repeated for each of the nine components at each power level. The Nusselt Number was then calculated from Equation 3.1.

2. Determination of the Rayleigh Numbers

The definition of the temperature based Rayleigh number is:

$$Ra_t = Gr_t * Pr \quad (3.7)$$

where the Grashof Number (Gr_t) is defined as,

$$Gr_t = \frac{g\beta L^3 (T_{avg} - T_c)}{\nu^2} \quad (3.8)$$

and the Prandtl Number (Pr) is defined as,

$$Pr = \frac{\nu}{\alpha} \quad (3.9)$$

where,

$$\alpha = \frac{k_f}{(\rho c_p)}$$

All the properties in the above equations are calculated at the average film temperature:

$$T_f = \frac{T_{avg} + T_c}{2} \quad (3.10)$$

Therefore:

$$Ra_t = \frac{g\beta L^3 (T_{avg} - T_c)}{\nu \alpha} \quad (3.11)$$

3. Determination of the Flux Based Rayleigh Number

The definition of the flux based Rayleigh number is:

$$Ra_f = Gr_f * Pr \quad (3.12)$$

all film properties are calculated at the average film temperature as before and:

$$Gr_f = \frac{g\beta L^4 Q_{net}}{k_f v^2 A_{tot}} \quad . \quad (3.13)$$

Functional relationships for the properties at the film temperature are given in Appendix A, together with sample calculations. Uncertainty calculations are given in Appendix B.

IV. RESULTS

A. FLOW VISUALIZATION

Flow visualization was accomplished using Magnesium particles as a flow marker and a Helium Neon laser to illuminate the particles. The results provided insights into the flow patterns existing at various power dissipation levels. As expected, the particle traces suggest highly three-dimensional flow patterns at all power levels. Particles can be seen entering and leaving the plane of light in almost all the long time exposure photographs. A multitude of flow patterns was observed for the wide range of input power levels in the of 0.1 to 3.1 watts. Representative flow visualizations are presented in Figures 4.1 to 4.14.

1. Flow Patterns at Component Midplanes

The following flow patterns are in a vertical plane through the center of components 4, 5, 6 (Fig. 2.2). The laser was placed in front of the chamber and the camera located to the side (Fig. 2.5). The camera exposure time was set at 10 seconds. The three dark regions located on the left side of the photographs are the three rows of components as seen in side view. The top and bottom of the chamber and the horizontal walls can also be seen in the photos.

Figure 4.1 is the flow pattern for a power input of 0.1 watts and indicates a pattern that contains two individual eddies located between the rows of components along with an overall circular pattern that encompasses the entire chamber. A boundary layer like flow is seen in the vicinity of the heated components. A dark region located at the bottom of the photograph is evident in all photos taken throughout the experiment. This region is the stagnant, dense cold fluid layer in the vicinity of the bottom heat exchanger. This region proved to be impermeable at all power levels.

Figure 4.2 for power input of 0.3 watts indicates the same overall pattern with the exception of a constriction of the overall circular pattern at the approximate height of the second row of components. The slight increase in the upper eddy size is also evident.

Figure 4.3 for a power input of 1.5 watts indicates an increase in the thickness of the boundary layer emanating from the second row of components along with increased entrainment of the particles located below the second row of components. Also evident is the disappearance of the two distinct eddies seen earlier and strong evidence of three dimensionality in the flow as seen by the crossing of the particle paths.



Figure 4.1 Power @ 0.1 W
Side View



Figure 4.2 Power @ 0.3 W
Side View



Figure 4.3 Power @ 1.5 W
Side View

Figure 4.4, for a power input of 2.7 watts, shows a buoyant fluid layer adjacent to the components and random motion throughout the remaining chamber. Also seen are entrainment of particles at the approximate height of the second row of components, and evidence of an area, immediately above the black region at the photo's bottom, where particles are basically suspended.

Figure 4.5, at 3.1 watts, demonstrated a downward flow pattern in the vicinity of the bottom row. This downward flow was forced past the face of the bottom chip in this column. The flow also demonstrated a perpendicular entrainment of particles between the first and second row of components, and a large increase in the boundary layer at the third row of components.

Figures 4.6 and 4.7 show flow patterns in the vertical plane at the mid-span of components 7, 8 and 9. These two photographs were taken approximately 5 seconds apart at a power setting of 3.1 watts. They demonstrate the strongly time-dependent behavior of the flow. In Figure 4.6, entrainment into the upward moving buoyant layer is seen to be present almost as far down as the bottom of the lowest component. Far away from the components the core fluid exhibits no preferential direction of motion. In Figure 4.7 the flow pattern has changed. Near the lowest row of components the flow now appears almost quiescent. Also, the buoyant region appears thinner than in Figure 4.6.



Figure 4.4 Power @ 2.7 W
Side View



Figure 4.5 Power @ 3.1 W
Side View



Figure 4.6 Power @ 3.1 W
Side View,
Chips 7, 8, 9



Figure 4.7 Power @ 3.1 W
Side View,
Chips 7, 8, 9

2. Flow Patterns in Other Planes

Figure 4.8 is a schematic of the three planes that were investigated when the positions of the camera and the laser were reversed. Figures 4.9, 4.10 and 4.11 are at a power setting of 0.1 watts and demonstrate the flow patterns in the back, middle and front planes, respectively. In Figure 4.9, the back plane, the flow appears to be somewhat like a large circular pattern that is bounded by the physical dimensions of the chamber and exhibits no noticeable flow directly up the center of the chamber. Figure 4.10, the middle plane, indicates a strong upward flow in the center of the chamber and two areas of eddy formation located approximately mid-height in the chamber. Finally, Figure 4.11, the front plane, demonstrated approximately the same behavior as the middle plane; a general area of motion in the center of the chamber along with eddy formation areas on either side.

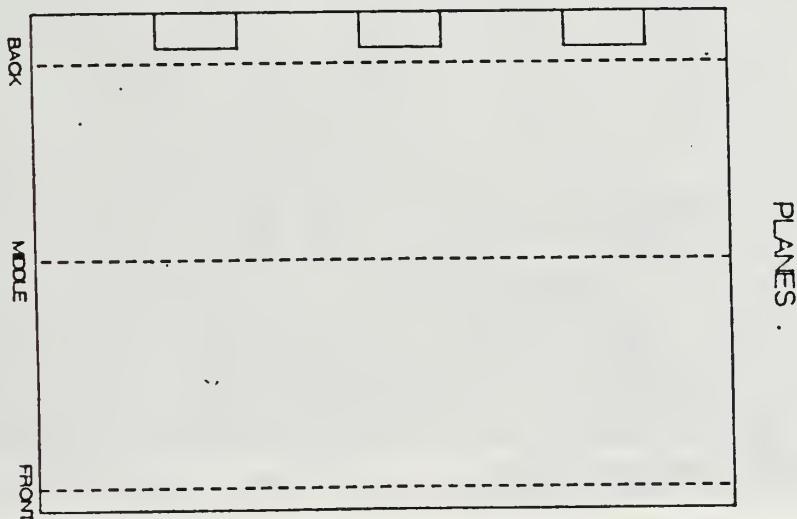


Figure 4.8 Top View of Planes

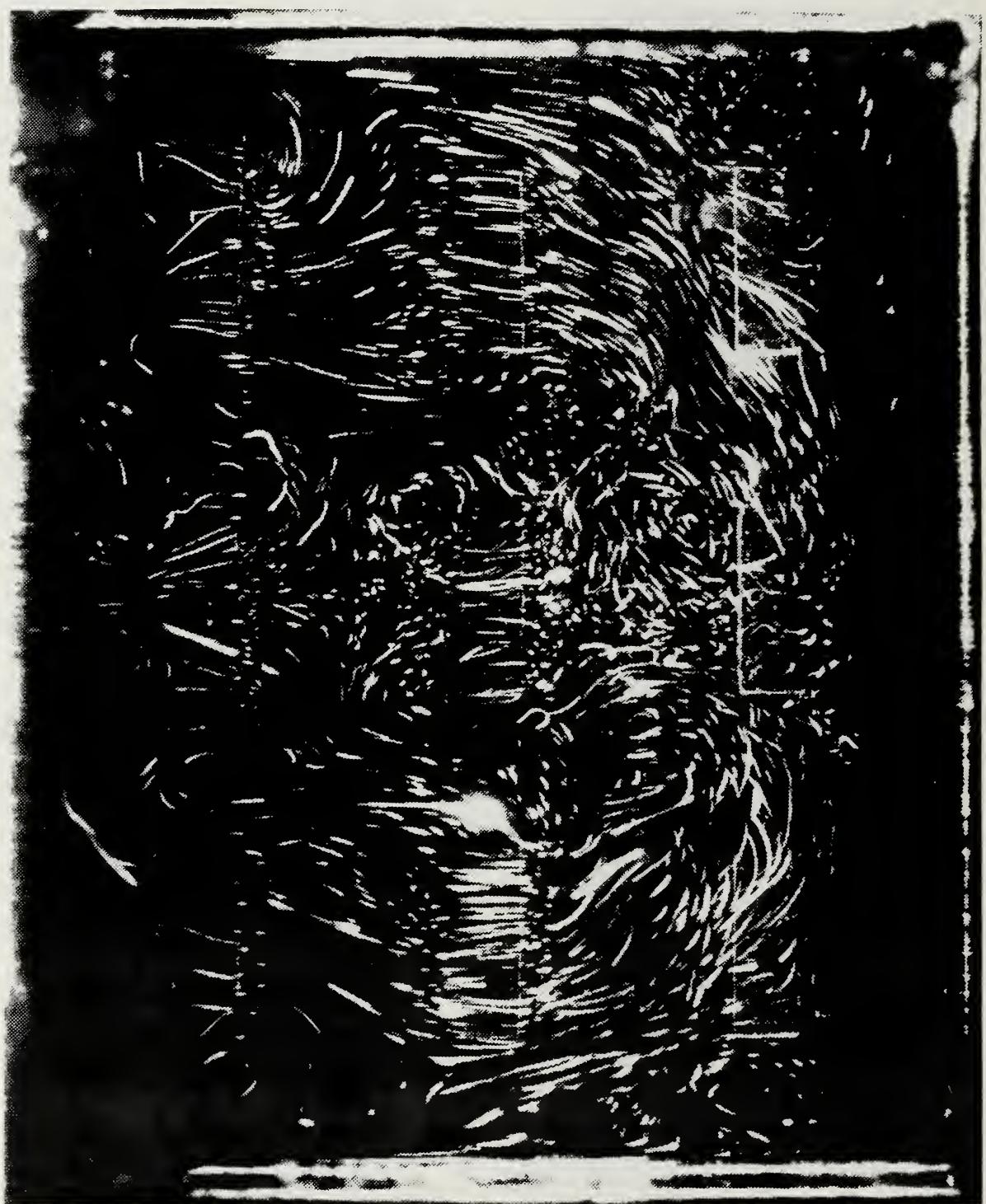


Figure 4.9 Back Plane @ 0.1 Watts

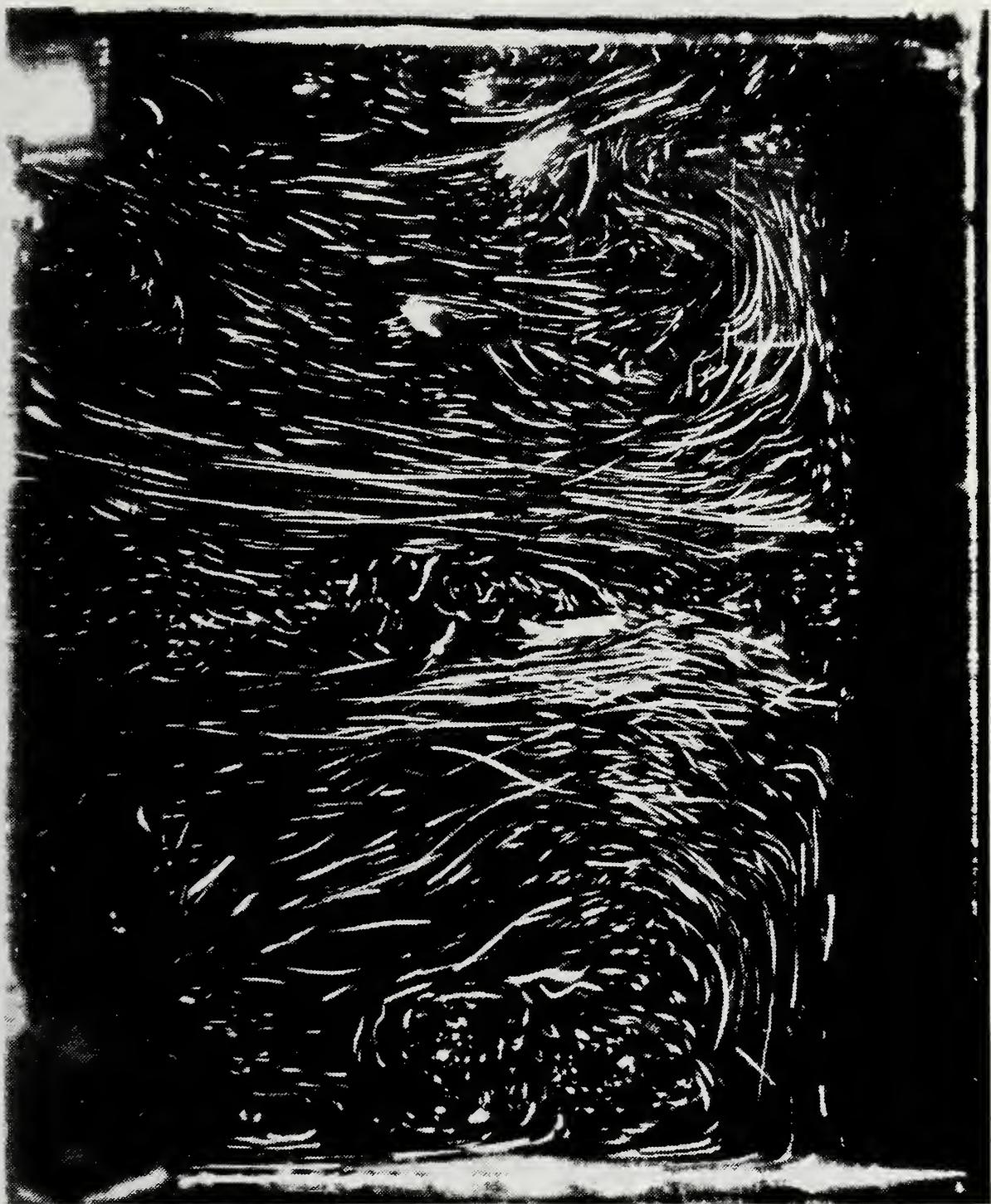


Figure 4.10 Middle Plane @ 0.1 Watts



Figure 4.11 Front Plane @ 0.1 Watts

Figures 4.12, 4.13 and 4.14 are the same three planes at a power setting of 3.1 watts. Figure 4.12, the back plane, indicates regions of upward flow near the components. These patterns characterize the boundary layer nature of transport in the vicinity of the elements. Relatively short particle traces in regions away from the components appear to result due to the strongly three-dimensional transport. The dark area in the very bottom of the photograph is again pointed out to demonstrate the cold isothermal layer developed by the bottom heat exchanger.

Figures 4.13 and 4.14 are views of the center and front planes respectively. The flow in both planes appears strongly time dependent. Figure 4.14 shows relatively longer particle traces than Figure 4.13, indicating stronger three dimensional effects near the components.

These 13 photographs illustrate the complex three-dimensional, time dependent flow patterns found in this study. Obtaining a detailed understanding of these effects is essential in achieving predictive capability for the heat transfer in these configurations.

B. REDUCTION OF HEAT TRANSFER DATA

The temperature and reduced data tables corresponding to the eight power levels are as follows: (see Figure 2.2 for identification of the component numbers).

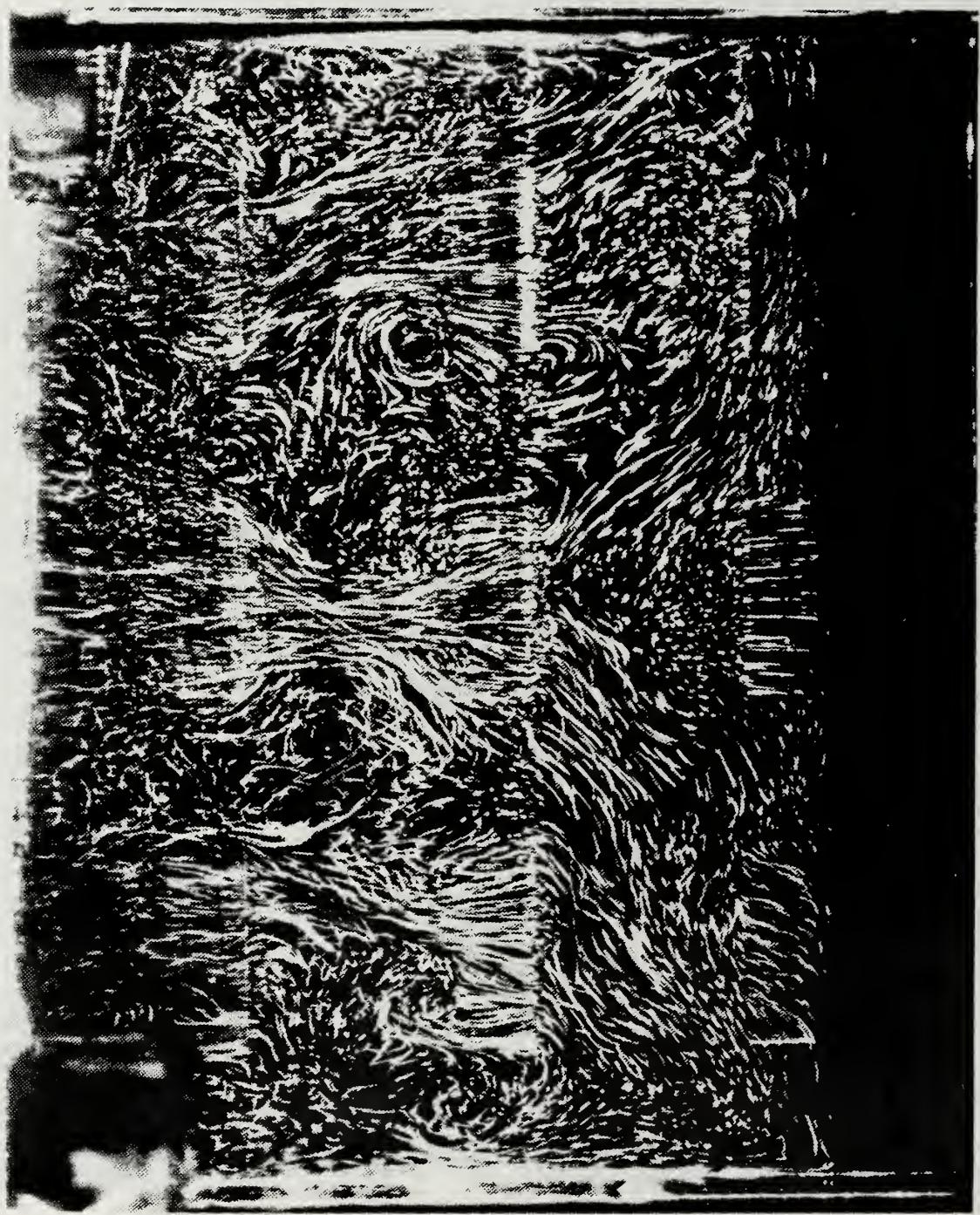


Figure 4.12 Back Plane @ 3.1 Watts

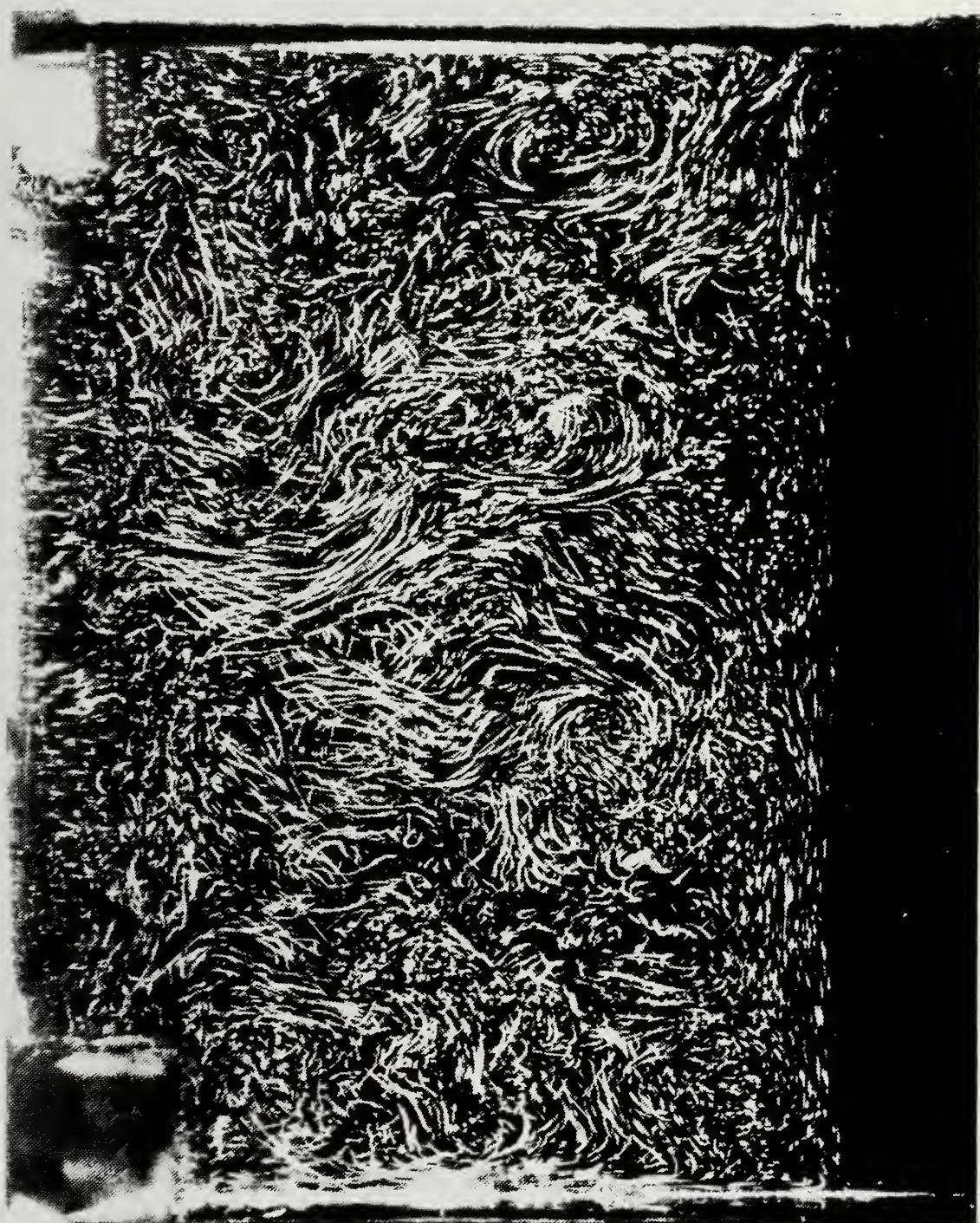


Figure 4.13 Middle Plane @ 3.1 Watts

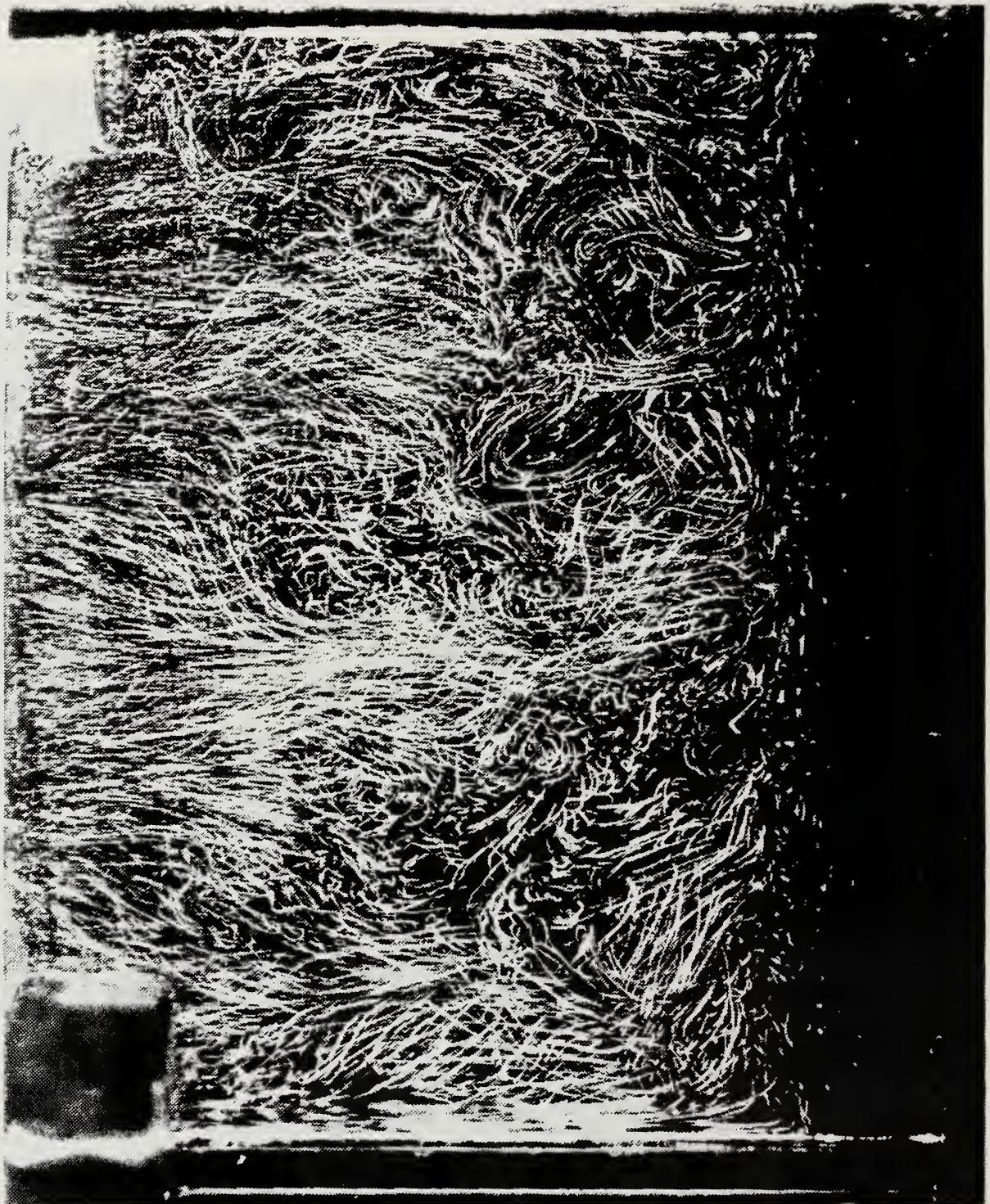


Figure 4.14 Front Plane @ 3.1 Watts

TABLE 1

TEMPERATURE DATA FOR INPUT POWER $Q_{in} = 0.3$ W

THESE RESULTS ARE STORED IN FILE: D809811CO

AMBIENT TEMP WAS: 23 C
 VOLTMETER READING WAS: 2.0082 #61
 BATH TEMP WAS: 10 C
 THIS RUN WAS RECORDED WITH FLOW VIZ

ALL TEMPERATURES ARE IN DEGREES CELCIUS

	CENTER	TOP	RIGHT	LEFT	BOTTOM	BACK
CHIP N01:	16.54E+00	16.33E+00	16.15E+00	16.16E+00	16.11E+00	16.55E+00
POWER (WATTS):	29.93E-02					
CHIP N02:	16.68E+00	16.31E+00	16.34E+00	16.19E+00	16.30E+00	17.53E+00
POWER (WATTS):	29.94E-02					
CHIP N03:	16.74E+00	16.32E+00	16.46E+00	16.33E+00	16.63E+00	17.40E+00
POWER (WATTS):	29.83E-02					
CHIP N04:	16.52E+00	16.33E+00	16.08E+00	15.82E+00	16.02E+00	15.33E+00
POWER (WATTS):	29.55E-02					
CHIP N05:	16.52E+00	16.15E+00	16.12E+00	16.05E+00	16.30E+00	17.11E+00
POWER (WATTS):	29.67E-02					
CHIP N06:	16.51E+00	16.50E+00	16.33E+00	16.33E+00	16.58E+00	18.10E+00
POWER (WATTS):	29.64E-02					
CHIP N07:	16.64E+00	16.42E+00	16.12E+00	16.12E+00	16.32E+00	17.31E+00
POWER (WATTS):	30.01E-02					
CHIP N08:	16.71E+00	16.42E+00	16.40E+00	16.40E+00	16.28E+00	18.02E+00
POWER (WATTS):	30.12E-02					
CHIP N09:	16.65E+00	16.39E+00	16.23E+00	16.36E+00	16.41E+00	17.69E+00
POWER (WATTS):	29.87E-02					

HEAT EXCHANGERS TEMPERATURES: RIGHT LEFT
 BOTTOM: 99.12E-01 99.39E-01
 TOP: 10.38E+00 98.03E-01

BACK PLANE TEMPERATURES ARE :

T(55): 14.67E+00
 T(56): 15.41E+00
 T(57): 15.27E+00
 T(72): 15.57E+00
 T(73): 15.55E+00
 T(74): 16.06E+00
 T(75): 15.56E+00
 T(76): 15.56E+00
 T(77): 15.45E+00

TABLE 2

TEMPERATURE DATA FOR INPUT POWER $Q_{in} = 0.7$ W

THESE RESULTS ARE STORED IN FILE: D80922100

AMBIENT TEMP WAS: 23 C
 VOLTMETER READING WAS: 3.2198 #61
 BATH TEMP WAS: 10 C
 THIS RUN WAS RECORDED WITH FLOW VIZ

ALL TEMPERATURES ARE IN DEGREES CELCIUS

CENTER	TOP	RIGHT	LEFT	BOTTOM	BACK
CHIP N01:	23.35E+00	22.53E+00	22.35E+00	22.39E+00	22.24E+00
POWER (WATTS):	71.08E-02				24.06E+00
CHIP N02:	23.36E+00	22.37E+00	22.43E+00	22.09E+00	22.39E+00
POWER (WATTS):	71.11E-02				25.05E+00
CHIP N03:	23.16E+00	22.36E+00	22.55E+00	22.14E+00	22.73E+00
POWER (WATTS):	70.87E-02				24.58E+00
CHIP N04:	23.23E+00	22.42E+00	22.31E+00	21.69E+00	22.16E+00
POWER (WATTS):	70.18E-02				24.16E+00
CHIP N05:	23.11E+00	21.96E+00	21.94E+00	21.85E+00	22.37E+00
POWER (WATTS):	70.47E-02				24.19E+00
CHIP N06:	22.69E+00	22.77E+00	22.18E+00	22.21E+00	22.60E+00
POWER (WATTS):	70.38E-02				26.12E+00
CHIP N07:	23.49E+00	22.76E+00	22.17E+00	22.15E+00	22.39E+00
POWER (WATTS):	71.26E-02				24.55E+00
CHIP N08:	23.32E+00	22.63E+00	22.47E+00	22.55E+00	22.47E+00
POWER (WATTS):	71.55E-02				26.17E+00
CHIP N09:	23.07E+00	22.54E+00	22.05E+00	22.38E+00	22.20E+00
POWER (WATTS):	70.95E-02				25.41E+00

HEAT EXCHANGERS TEMPERATURES: RIGHT LEFT
 BOTTOM: 98.18E-01 98.46E-01
 TOP: 98.21E-01 93.58E-01

BACK PLANE TEMPERATURES ARE :

T(55): 17.67E+00
 T(56): 18.76E+00
 T(57): 19.05E+00
 T(72): 19.08E+00
 T(73): 18.90E+00
 T(74): 19.11E+00
 T(75): 19.02E+00
 T(76): 18.79E+00
 T(77): 18.71E+00

TABLE 3

TEMPERATURE DATA FOR INPUT POWER $Q_{in} = 1.1 \text{ W}$

THESE RESULTS ARE STORED IN FILE: D80990745

AMBIENT TEMP WAS: 23 C
 VOLTMETER READING WAS: 4.1107 V
 BATH TEMP WAS: 10 C
 THIS RUN WAS RECORDED WITH FLOW VIZ

ALL TEMPERATURES ARE IN DEGREES CELCIUS

CENTER	TOP	RIGHT	LEFT	BOTTOM	BACK
CHIP N01:	28.62E+00	27.35E+00	27.13E+00	27.16E+00	26.93E+00
POWER (WATTS):	11.57E-01				29.81E+00
CHIP N02:	28.73E+00	27.05E+00	27.13E+00	26.72E+00	27.11E+00
POWER (WATTS):	11.58E-01				31.43E+00
CHIP N03:	28.47E+00	27.17E+00	27.49E+00	26.82E+00	27.69E+00
POWER (WATTS):	11.54E-01				30.65E+00
CHIP N04:	28.47E+00	27.04E+00	27.14E+00	26.18E+00	26.95E+00
POWER (WATTS):	11.43E-01				30.10E+00
CHIP N05:	28.21E+00	26.29E+00	26.42E+00	26.30E+00	27.03E+00
POWER (WATTS):	11.48E-01				30.00E+00
CHIP N06:	27.45E+00	27.90E+00	26.98E+00	27.00E+00	27.76E+00
POWER (WATTS):	11.46E-01				33.28E+00
CHIP N07:	29.12E+00	27.77E+00	27.03E+00	26.97E+00	27.25E+00
POWER (WATTS):	11.60E-01				30.66E+00
CHIP N08:	28.56E+00	27.45E+00	27.27E+00	27.40E+00	27.18E+00
POWER (WATTS):	11.65E-01				33.20E+00
CHIP N09:	28.13E+00	27.32E+00	26.60E+00	27.12E+00	26.72E+00
POWER (WATTS):	11.55E-01				32.07E+00

HEAT EXCHANGERS TEMPERATURES: RIGHT LEFT
 BOTTOM: . 99.44E-01 99.77E-01
 TOP: 10.05E+00 96.50E-01

BACK PLANE TEMPERATURES ARE :

T(55): 19.74E+00
 T(56): 21.13E+00
 T(57): 21.79E+00
 T(72): 21.42E+00
 T(73): 21.14E+00
 T(74): 21.41E+00
 T(75): 21.53E+00
 T(76): 20.93E+00
 T(77): 20.82E+00

TABLE 4
TEMPERATURE DATA FOR INPUT POWER $Q_{in} = 1.5$ W

THESE RESULTS ARE STORED IN FILE: D80992015

AMBIENT TEMP WAS: 23 C
VOLTMETER READING WAS: 4.6442 •61
BATH TEMP WAS: 10 C
THIS RUN WAS RECORDED WITH FLOW VIZ

ALL TEMPERATURES ARE IN DEGREES CELCIUS

CENTER	TOP	RIGHT	LEFT	BOTTOM	BACK
CHIP N01:	32.81E+00	31.19E+00	31.03E+00	31.08E+00	30.78E+00
POWER (WATTS):	14.77E-01				34.47E+00
CHIP N02:	32.92E+00	30.93E+00	31.02E+00	30.42E+00	31.07E+00
POWER (WATTS):	14.77E-01				36.44E+00
CHIP N03:	32.36E+00	30.95E+00	31.32E+00	30.50E+00	31.66E+00
POWER (WATTS):	14.72E-01				35.33E+00
CHIP N04:	32.60E+00	30.86E+00	31.04E+00	29.86E+00	30.79E+00
POWER (WATTS):	14.58E-01				34.86E+00
CHIP N05:	32.28E+00	29.79E+00	30.12E+00	29.99E+00	30.81E+00
POWER (WATTS):	14.64E-01				34.66E+00
CHIP N06:	30.86E+00	31.77E+00	30.66E+00	30.72E+00	31.43E+00
POWER (WATTS):	14.62E-01				39.92E+00
CHIP N07:	33.43E+00	31.83E+00	30.89E+00	30.81E+00	31.12E+00
POWER (WATTS):	14.80E-01				35.45E+00
CHIP N08:	32.82E+00	31.45E+00	31.27E+00	31.40E+00	31.22E+00
POWER (WATTS):	14.87E-01				38.77E+00
CHIP N09:	32.21E+00	31.07E+00	30.36E+00	30.97E+00	30.30E+00
POWER (WATTS):	14.74E-01				37.25E+00

HEAT EXCHANGERS TEMPERATURES: RIGHT LEFT
 BOTTOM: 99.49E-01 99.69E-01
 TOP: 99.69E-01 95.79E-01

BACK PLANE TEMPERATURES ARE :

T(55): 21.87E+00
 T(56): 23.45E+00
 T(57): 24.33E+00
 T(72): 23.84E+00
 T(73): 23.52E+00
 T(74): 23.83E+00
 T(75): 24.10E+00
 T(76): 23.25E+00
 T(77): 23.10E+00

TABLE 5

TEMPERATURE DATA FOR INPUT POWER $Q_{in} = 1.9 \text{ W}$

THESE RESULTS ARE STORED IN FILE: D81001130

AMBIENT TEMP WAS: 23 C
 VOLTMETER READING WAS: 5.2844 ±51
 BATH TEMP WAS: 10 C
 THIS RUN WAS RECORDED WITH FLOW VIZ

ALL TEMPERATURES ARE IN DEGREES CELCIUS

CENTER	TOP	RIGHT	LEFT	BOTTOM	BACK
CHIP N01:	37.45E+00	35.42E+00	35.24E+00	35.29E+00	34.90E+00
POWER (WATTS):	19.10E-01				39.63E+00
CHIP N02:	37.46E+00	34.63E+00	35.00E+00	34.29E+00	34.99E+00
POWER (WATTS):	19.11E-01				42.43E+00
CHIP N03:	36.50E+00	34.89E+00	35.33E+00	34.33E+00	35.51E+00
POWER (WATTS):	19.05E-01				40.46E+00
CHIP N04:	37.22E+00	34.98E+00	35.28E+00	33.81E+00	35.01E+00
POWER (WATTS):	18.86E-01				40.20E+00
CHIP N05:	36.70E+00	33.55E+00	34.01E+00	33.86E+00	34.97E+00
POWER (WATTS):	18.94E-01				39.83E+00
CHIP N06:	35.05E+00	36.55E+00	34.59E+00	34.95E+00	35.73E+00
POWER (WATTS):	18.90E-01				48.38E+00
CHIP N07:	38.33E+00	36.17E+00	35.13E+00	34.99E+00	35.34E+00
POWER (WATTS):	19.15E-01				40.79E+00
CHIP N08:	37.38E+00	35.81E+00	35.42E+00	35.57E+00	35.43E+00
POWER (WATTS):	19.23E-01				45.03E+00
CHIP N09:	36.47E+00	35.22E+00	34.36E+00	35.10E+00	34.40E+00
POWER (WATTS):	19.07E-01				43.13E+00

HEAT EXCHANGERS TEMPERATURES:	RIGHT	LEFT
BOTTOM:	99.84E-01	10.02E+00
TOP:	95.29E-01	92.47E-01

BACK PLANE TEMPERATURES ARE :

T(55):	23.54E+00
T(56):	25.35E+00
T(57):	26.58E+00
T(72):	25.81E+00
T(73):	25.38E+00
T(74):	25.72E+00
T(75):	26.29E+00
T(76):	25.04E+00
T(77):	24.85E+00

TABLE 6

TEMPERATURE DATA FOR INPUT POWER $Q_{in} = 2.3 \text{ W}$

THESE RESULTS ARE STORED IN FILE: D81001740

AMBIENT TEMP WAS: 23 C
 VOLTMETER READING WAS: 5.8093 V
 BATH TEMP WAS: 10 C
 THIS RUN WAS RECORDED WITH FLOW VIZ

ALL TEMPERATURES ARE IN DEGREES CELCIUS

	CENTER	TOP	RIGHT	LEFT	BOTTOM	BACK
CHIP N01:	42.48E+00	39.94E+00	39.75E+00	39.90E+00	39.39E+00	45.05E+00
POWER (WATTS):	23.07E-01					
CHIP N02:	42.44E+00	39.26E+00	39.57E+00	38.83E+00	39.51E+00	48.58E+00
POWER (WATTS):	23.08E-01					
CHIP N03:	41.90E+00	39.50E+00	40.09E+00	38.99E+00	40.59E+00	46.17E+00
POWER (WATTS):	23.00E-01					
CHIP N04:	42.09E+00	39.24E+00	39.82E+00	38.09E+00	39.48E+00	45.71E+00
POWER (WATTS):	22.78E-01					
CHIP N05:	41.49E+00	37.80E+00	38.35E+00	38.17E+00	39.60E+00	45.28E+00
POWER (WATTS):	22.88E-01					
CHIP N06:	39.67E+00	41.33E+00	38.98E+00	39.52E+00	40.48E+00	56.04E+00
POWER (WATTS):	22.82E-01					
CHIP N07:	43.53E+00	40.80E+00	39.71E+00	39.58E+00	39.89E+00	46.53E+00
POWER (WATTS):	23.12E-01					
CHIP N08:	42.48E+00	40.36E+00	40.09E+00	40.20E+00	39.57E+00	51.52E+00
POWER (WATTS):	23.22E-01					
CHIP N09:	41.70E+00	39.86E+00	38.85E+00	39.61E+00	38.95E+00	49.58E+00
POWER (WATTS):	23.03E-01					

HEAT EXCHANGERS TEMPERATURES: RIGHT LEFT
 BOTTOM: . 10.00E+00 10.04E+00
 TOP: 10.14E+00 10.06E+00

BACK PLANE TEMPERATURES ARE :

T(55): 25.69E+00
 T(56): 27.76E+00
 T(57): 29.42E+00
 T(72): 28.37E+00
 T(73): 27.87E+00
 T(74): 28.23E+00
 T(75): 29.04E+00
 T(76): 27.41E+00
 T(77): 27.19E+00

TABLE 7

TEMPERATURE DATA FOR INPUT POWER $Q_{in} = 2.7 \text{ W}$

THESE RESULTS ARE STORED IN FILE: D81011130

AMBIENT TEMP WAS: 23 C
 VOLTMETER READING WAS: 5.344 ±51
 BATH TEMP WAS: 10 C
 THIS RUN WAS RECORDED WITH FLOW VIZ

ALL TEMPERATURES ARE IN DEGREES CELCIUS

	CENTER	TOP	RIGHT	LEFT	BOTTOM	BACK
CHIP N01:	46.68E+00	43.58E+00	43.37E+00	43.69E+00	43.06E+00	49.81E+00
POWER (WATTS):	27.60E-01					
CHIP N02:	46.25E+00	43.02E+00	43.14E+00	42.04E+00	42.86E+00	53.82E+00
POWER (WATTS):	27.51E-01					
CHIP N03:	45.70E+00	43.18E+00	43.85E+00	42.33E+00	44.32E+00	50.88E+00
POWER (WATTS):	27.52E-01					
CHIP N04:	46.22E+00	42.88E+00	43.55E+00	41.56E+00	43.20E+00	50.62E+00
POWER (WATTS):	27.26E-01					
CHIP N05:	45.45E+00	40.81E+00	41.67E+00	41.55E+00	43.18E+00	49.94E+00
POWER (WATTS):	27.37E-01					
CHIP N06:	43.55E+00	45.08E+00	41.98E+00	43.23E+00	44.00E+00	63.01E+00
POWER (WATTS):	27.29E-01					
CHIP N07:	47.86E+00	44.69E+00	43.43E+00	43.20E+00	43.56E+00	51.81E+00
POWER (WATTS):	27.66E-01					
CHIP N08:	46.05E+00	43.92E+00	43.56E+00	43.77E+00	43.34E+00	57.24E+00
POWER (WATTS):	27.78E-01					
CHIP N09:	44.78E+00	43.22E+00	41.99E+00	42.90E+00	41.90E+00	55.35E+00
POWER (WATTS):	27.55E-01					

HEAT EXCHANGERS TEMPERATURES: RIGHT LEFT
 BOTTOM: 99.27E-01 99.49E-01
 TOP: 10.00E+00 98.46E-01

BACK PLANE TEMPERATURES ARE :

T(55): 26.87E+00
 T(56): 29.09E+00
 T(57): 31.13E+00
 T(72): 29.93E+00
 T(73): 29.33E+00
 T(74): 29.77E+00
 T(75): 30.78E+00
 T(76): 28.82E+00
 T(77): 28.57E+00

TABLE 8

TEMPERATURE DATA FOR INPUT POWER $Q_{in} = 3.1 \text{ W}$

THESE RESULTS ARE STORED IN FILE: D81011515

AMBIENT TEMP WAS: 23 C
 VOLTMETER READING WAS: 6.8019 *61
 BATH TEMP WAS: 10 C
 THIS RUN WAS RECORDED WITH FLOW VIZ

ALL TEMPERATURES ARE IN DEGREES CELCIUS

	CENTER	TOP	RIGHT	LEFT	BOTTOM	BACK
CHIP N01:	50.27E+00	46.37E+00	46.67E+00	46.36E+00	46.34E+00	54.20E+00
POWER (WATTS):	31.58E-01					
CHIP N02:	49.47E+00	45.72E+00	45.94E+00	44.88E+00	45.65E+00	58.34E+00
POWER (WATTS):	31.60E-01					
CHIP N03:	48.49E+00	45.75E+00	46.70E+00	44.97E+00	47.04E+00	54.80E+00
POWER (WATTS):	31.50E-01					
CHIP N04:	49.72E+00	46.06E+00	46.89E+00	44.65E+00	46.51E+00	55.03E+00
POWER (WATTS):	31.19E-01					
CHIP N05:	48.67E+00	43.79E+00	44.88E+00	44.50E+00	46.45E+00	54.10E+00
POWER (WATTS):	31.32E-01					
CHIP N06:	46.42E+00	48.26E+00	44.90E+00	46.17E+00	47.08E+00	68.15E+00
POWER (WATTS):	31.23E-01					
CHIP N07:	51.67E+00	48.20E+00	46.82E+00	46.51E+00	46.95E+00	56.86E+00
POWER (WATTS):	31.66E-01					
CHIP N08:	49.44E+00	46.99E+00	46.61E+00	46.80E+00	46.32E+00	62.31E+00
POWER (WATTS):	31.80E-01					
CHIP N09:	48.20E+00	46.19E+00	44.97E+00	46.00E+00	45.25E+00	60.81E+00
POWER (WATTS):	31.53E-01					

HEAT EXCHANGERS TEMPERATURES: RIGHT LEFT
 BOTTOM: 10.02E+00 10.05E+00
 TOP: 10.09E+00 99.64E-01

BACK PLANE TEMPERATURES ARE :

T(55): 28.58E+00
 T(56): 30.93E+00
 T(57): 33.10E+00
 T(72): 31.64E+00
 T(73): 31.01E+00
 T(74): 31.47E+00
 T(75): 32.56E+00
 T(76): 30.45E+00
 T(77): 30.21E+00

TABLE 9

REDUCED DATA FOR INPUT POWER $Q_{in} = 0.3$ W

THE RAW EMF DATA ARE FROM THE FILE: D80700925
 THE POWER SETTING PER CHIP WAS: 0.3 WATTS

CHIP	QNET(W)	Tavg-Ts	Nu	%UNC IN Nu
1	27.38E-02	56.09E-01	10.61E+00	20.55E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 104.43E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :179.04E-02			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 110.76E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 100.88E-02			
2	27.38E-02	57.60E-01	10.33E+00	20.14E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 107.44E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :174.32E-02			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 110.98E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 100.88E-02			
3	27.29E-02	57.70E-01	10.28E+00	20.12E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 107.63E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :174.03E-02			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 110.63E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 100.88E-02			
4	27.03E-02	55.15E-01	10.65E+00	20.82E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 102.58E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :182.08E-02			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 109.23E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 100.89E-02			
5	27.14E-02	56.58E-01	10.42E+00	20.42E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 105.40E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :177.49E-02			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 109.86E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 100.89E-02			
6	27.11E-02	58.16E-01	10.13E+00	20.00E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 108.54E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :172.66E-02			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 109.94E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 100.89E-02			
7	27.45E-02	56.19E-01	10.62E+00	20.52E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 104.64E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :178.71E-02			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 111.08E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 100.88E-02			
8	27.56E-02	58.00E-01	10.33E+00	20.04E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 108.23E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :173.13E-02			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 111.75E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 100.87E-02			
9	27.33E-02	57.25E-01	10.37E+00	20.23E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 106.74E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :175.40E-02			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 110.70E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 100.88E-02			

TABLE 10
REDUCED DATA FOR INPUT POWER $Q_{in} = 0.7$ W

THE RAW EMF DATA ARE FROM THE FILE: D80701535
THE POWER SETTING PER CHIP WAS: 0.7 WATTS

CHIP	$Q_{NET}(W)$	T_{avg-T_s}	Nu	%UNC IN Nu
1	70.30E-02	11.51E+00	13.32E+00	13.35E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 228.83E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :872.27E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 304.72E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.05E-02			
2	70.32E-02	11.51E+00	13.32E+00	13.35E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 228.84E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :872.24E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 304.80E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.05E-02			
3	70.09E-02	11.51E+00	13.28E+00	13.35E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 228.78E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :872.44E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 303.80E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.06E-02			
4	69.41E-02	11.36E+00	13.32E+00	13.43E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 225.48E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :883.80E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 300.34E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.07E-02			
5	69.70E-02	11.23E+00	13.53E+00	13.49E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 222.64E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :893.83E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 301.13E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.06E-02			
6	69.61E-02	11.34E+00	13.38E+00	13.44E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 224.97E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :885.56E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 301.12E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.07E-02			
7	70.49E-02	11.57E+00	13.28E+00	13.32E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 230.19E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :867.69E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 305.75E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.05E-02			
8	70.78E-02	11.62E+00	13.28E+00	13.30E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 231.24E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :864.18E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 307.15E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.05E-02			
9	70.17E-02	11.34E+00	13.49E+00	13.43E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 225.08E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :885.19E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 303.58E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.06E-02			

TABLE 11

REDUCED DATA FOR INPUT POWER $Q_{in} = 1.1$ W

THE RAW EMF DATA ARE FROM THE FILE: D80711035
 THE POWER SETTING PER CHIP WAS: 1.1 WATTS

CHIP	$Q_{NET}(W)$	$T_{avg}-Ts$	Nu	%UNC IN Nu
1	11.45E-01	16.67E+00	15.01E+00	11.77E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 343.22E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :602.83E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 515.31E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.06E-02			
2	11.46E-01	16.59E+00	15.08E+00	11.78E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 341.44E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :605.54E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 515.06E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.06E-02			
3	11.42E-01	16.56E+00	15.06E+00	11.79E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 340.72E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :606.64E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 513.21E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.06E-02			
4	11.31E-01	16.41E+00	15.05E+00	11.82E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 337.05E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :612.23E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 507.35E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.07E-02			
5	11.35E-01	16.05E+00	15.45E+00	11.89E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 328.29E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :626.12E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 507.35E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.07E-02			
6	11.34E-01	15.92E+00	15.55E+00	11.92E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 325.25E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :631.11E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 505.88E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.07E-02			
7	11.48E-01	16.81E+00	14.93E+00	11.74E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 346.68E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :597.78E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 517.48E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.06E-02			
8	11.53E-01	16.76E+00	15.03E+00	11.75E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 345.42E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :599.62E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 519.33E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.05E-02			
9	11.43E-01	16.28E+00	15.34E+00	11.84E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 333.97E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :617.04E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 512.18E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.06E-02			

TABLE 12

REDUCED DATA FOR INPUT POWER $Q_{in} = 1.5 \text{ W}$

THE RAW EMF DATA ARE FROM THE FILE: D80720730
 THE POWER SETTING PER CHIP WAS: 1.5 WATTS

CHIP	$Q_{NET}(\text{W})$	$T_{avg}-T_s$	Nu	%UNC IN Nu
1	14.59E-01	19.05E+00	16.76E+00	11.41E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 401.43E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :527.67E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 672.71E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.12E-02			
2	14.59E-01	19.08E+00	16.74E+00	11.40E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 402.25E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :526.77E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 673.17E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.12E-02			
3	14.54E-01	19.35E+00	16.45E+00	11.37E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 409.23E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :519.31E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 673.03E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.12E-02			
4	14.40E-01	18.73E+00	16.83E+00	11.45E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 393.35E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :536.67E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 661.82E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.13E-02			
5	14.46E-01	18.39E+00	17.20E+00	11.49E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 385.00E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :546.38E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 662.05E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.13E-02			
6	14.44E-01	18.59E+00	16.99E+00	11.47E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 389.86E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :540.68E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 662.46E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.13E-02			
7	14.62E-01	19.27E+00	16.60E+00	11.38E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 407.23E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :521.42E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 676.12E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.11E-02			
8	14.68E-01	19.48E+00	16.50E+00	11.35E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 412.33E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :516.06E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 680.47E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.11E-02			
9	14.56E-01	19.09E+00	16.69E+00	11.40E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 402.60E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :526.39E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 671.79E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.12E-02			

TABLE 13

REDUCED DATA FOR INPUT POWER $Q_{in} = 1.9$ W

THE RAW EMF DATA ARE FROM THE FILE: D80721810
 THE POWER SETTING PER CHIP WAS: 1.9 WATTS

CHIP	QNET(W)	Tavg-Ts	Nu	%UNC IN Nu
1	18.99E-01	24.92E+00	16.75E+00	10.88E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 565.77E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :403.27E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 947.69E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.07E-02			
2	19.00E-01	24.72E+00	16.89E+00	10.89E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 560.03E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :406.56E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 945.98E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.07E-02			
3	18.94E-01	24.68E+00	16.86E+00	10.90E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 559.04E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :407.13E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 942.52E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.08E-02			
4	18.75E-01	24.53E+00	16.80E+00	10.91E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 554.73E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :409.65E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 931.79E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.09E-02			
5	18.83E-01	23.88E+00	17.32E+00	10.95E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 536.40E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :420.80E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 928.99E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.08E-02			
6	18.80E-01	23.83E+00	17.32E+00	10.95E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 535.00E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :421.68E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 926.84E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.09E-02			
7	19.04E-01	25.23E+00	16.59E+00	10.86E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 574.77E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :398.25E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 953.30E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.07E-02			
8	19.12E-01	25.20E+00	16.68E+00	10.86E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 573.88E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :398.74E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 957.00E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.07E-02			
9	18.96E-01	-24.47E+00	17.02E+00	10.91E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 552.91E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :410.73E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 941.24E-02			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.08E-02			

TABLE 14

REDUCED DATA FOR INPUT POWER $Q_{in} = 2.3$ W

THE RAW E_{mi} DATA ARE FROM THE FILE: D80731030
 THE POWER SETTING PER CHIP WAS: 2.3 WATTS

CHIP	$Q_{NET}(W)$	T_{avg-Ts}	Nu	%UNC IN Nu
1	22.85E-01	28.31E+00	17.76E+00	10.71E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 658.53E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :355.02E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 116.98E-01			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.07E-02			
2	22.86E-01	27.97E+00	17.98E+00	10.73E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 648.40E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :359.32E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 116.60E-01			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.07E-02			
3	22.78E-01	27.97E+00	17.93E+00	10.73E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 648.36E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :359.34E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 116.22E-01			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.07E-02			
4	22.56E-01	27.87E+00	17.81E+00	10.73E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 645.46E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :360.59E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 114.97E-01			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.08E-02			
5	22.65E-01	27.10E+00	18.38E+00	10.77E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 622.74E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :370.80E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 114.48E-01			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.08E-02			
6	22.60E-01	27.15E+00	18.31E+00	10.76E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 624.26E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :370.10E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 114.28E-01			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.08E-02			
7	22.90E-01	28.72E+00	17.55E+00	10.70E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 671.04E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :349.89E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 117.80E-01			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.07E-02			
8	23.00E-01	28.59E+00	17.71E+00	10.70E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 667.05E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :351.51E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 118.13E-01			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.06E-02			
9	22.80E-01	27.68E+00	18.13E+00	10.74E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 639.69E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :363.12E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 115.97E-01			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.07E-02			

TABLE 15

REDUCED DATA FOR INPUT POWER $Q_{in} = 2.7 \text{ W}$

THE RAW Emf DATA ARE FROM THE FILE: D80731755
 THE POWER SETTING PER CHIP WAS: 2.7 WATTS

CHIP	$Q_{NET}(\text{W})$	$T_{avg}-T_s$	Nu	%UNC IN Nu
1	27.37E-01	33.28E+00	18.16E+00	10.55E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 813.30E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :302.08E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 147.70E-01			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.05E-02			
2	27.39E-01	32.77E+00	18.44E+00	10.56E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 796.95E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :306.72E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 146.98E-01			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.05E-02			
3	27.30E-01	32.53E+00	18.52E+00	10.57E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 789.23E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :308.97E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 146.13E-01			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.05E-02			
4	27.03E-01	32.75E+00	18.22E+00	10.56E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 796.28E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :306.91E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 145.04E-01			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.06E-02			
5	27.15E-01	31.73E+00	18.87E+00	10.59E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 763.51E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :316.79E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 144.06E-01			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.06E-02			
6	27.07E-01	31.79E+00	18.78E+00	10.59E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 765.48E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :316.18E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 143.75E-01			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.06E-02			
7	27.44E-01	33.82E+00	17.92E+00	10.53E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 831.14E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :297.22E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 148.91E-01			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.05E-02			
8	27.56E-01	33.41E+00	18.21E+00	10.54E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 817.56E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :300.90E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 148.90E-01			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.04E-02			
9	27.32E-01	32.11E+00	18.77E+00	10.58E-01
	TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: 775.54E-02			
	% UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER IS :313.07E-03			
	FLUX BASED RAYLEIGH NUMBER * E-7 IS: 145.59E-01			
	% UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: 101.05E-02			

1. Graphical Representation of Reduced Data

The experimental surface temperature data were plotted as a dimensionless Nusselt Number vs. both a temperature based and a flux based Rayleigh Number, Figures 4.15 through 4.32.

Representative error bounds were plotted in Figures 4.15 and 4.16 for input powers of 1.5 and 1.9 watts. All points, with the exception of 1.5 watts were well within the error bounds. The point representing 1.5 watts was either too high on the Nusselt Number axis or too low on the Rayleigh number axis.

The factors affecting the Nusselt Number were h , L & K . Of these three, only h was calculated with uncertainty in this experiment. The factors affecting the Rayleigh Numbers were α , L , ΔT , Q_{net} , β , v and K . Of these only ΔT and Q_{net} had uncertainties.

Examination of Tables 4 and 12 resulted in no data which appeared to be extreme in either the raw or reduced data sets. One possible explanation for this point is the changing flow patterns around this power input. This may be a transition region from somewhat orderly flow to completely chaotic flow. It is recommended that further investigation of this region of power settings be conducted.

The equations for the best fit lines are very close to each other suggesting that an overall correlation that would produce good approximations is possible.

CHIP NUMBER 1

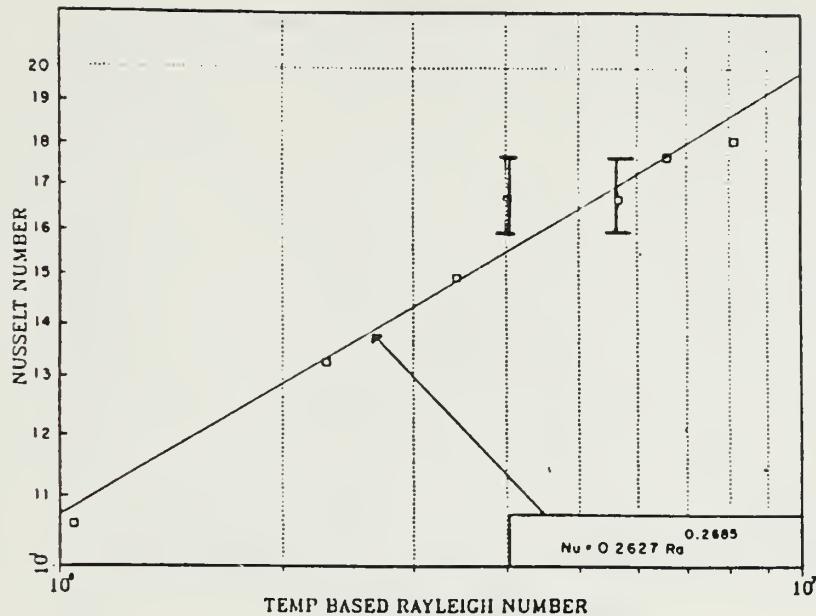


Figure 4.15 Temperature Based Rayleigh Numbers, Chip 1

CHIP NUMBER 1

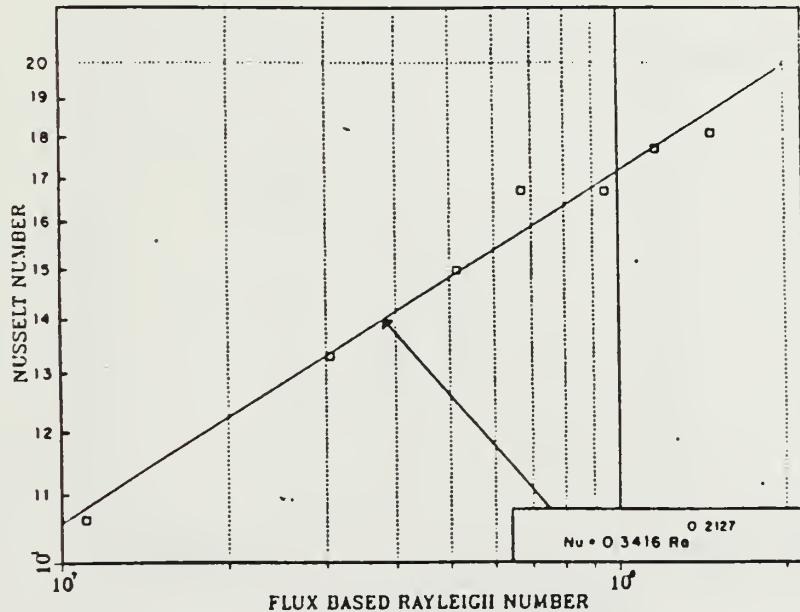


Figure 4.16 Flux Based Rayleigh Numbers, Chip 1

CHIP NUMBER 2

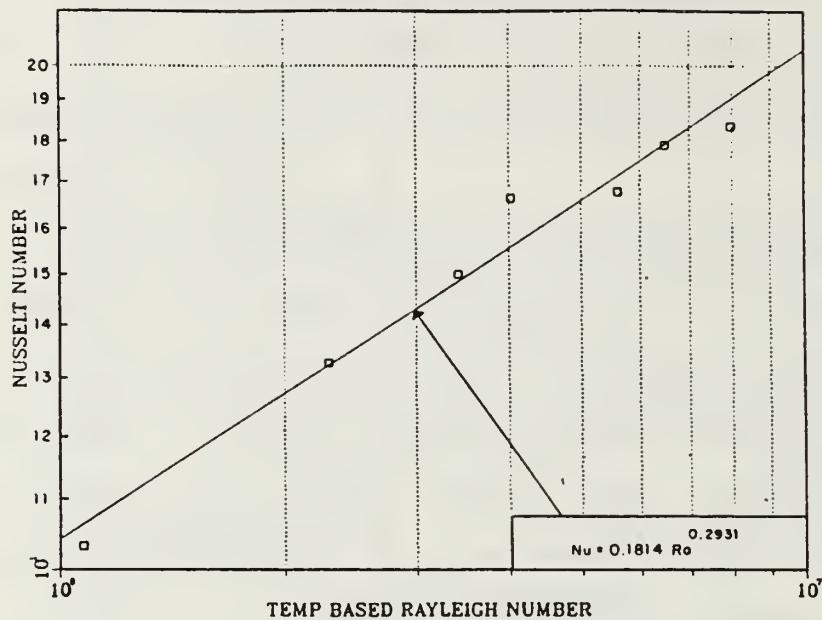


Figure 4.17 Temperature Based Rayleigh Numbers, Chip 2

CHIP NUMBER 2

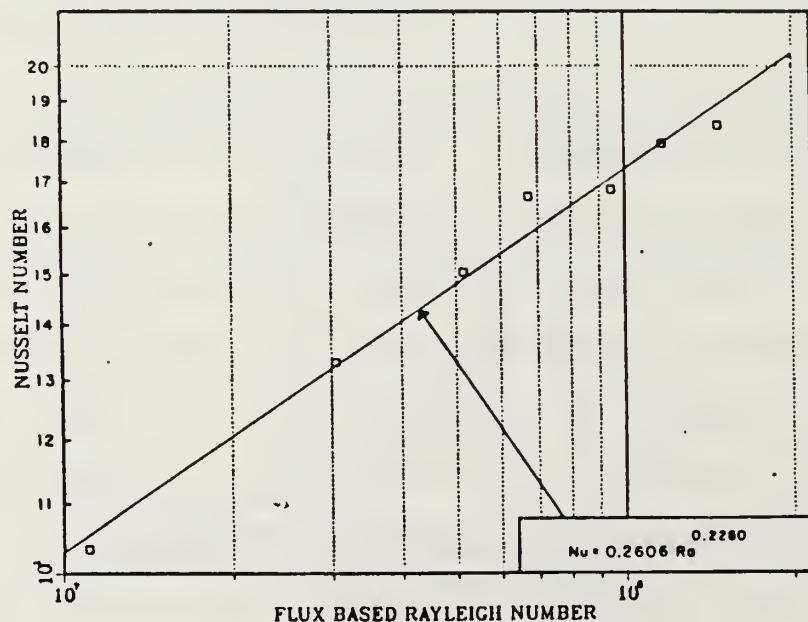


Figure 4.18 Flux Based Rayleigh Numbers, Chip 2

CHIP NUMBER 3

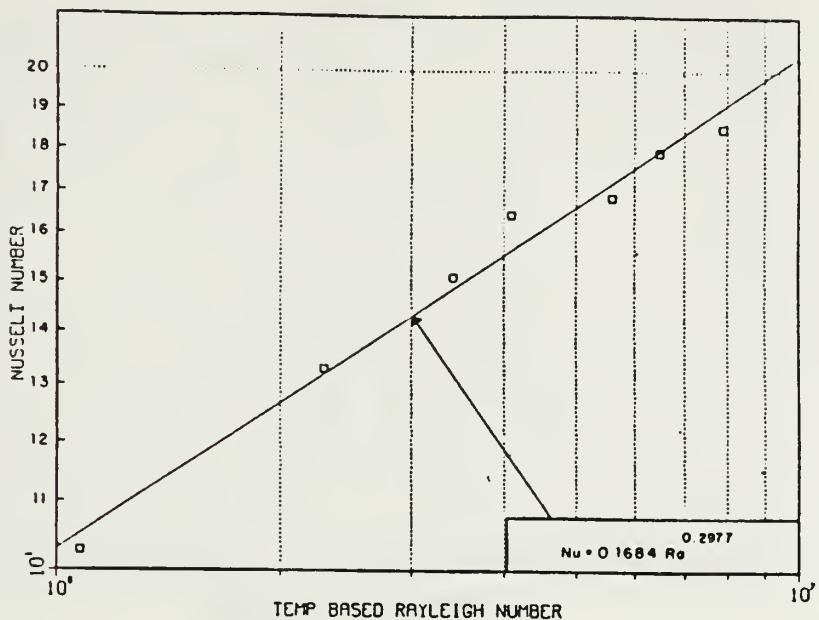


Figure 4.19 Temperature Based Rayleigh Numbers, Chip 3

CHIP NUMBER 3

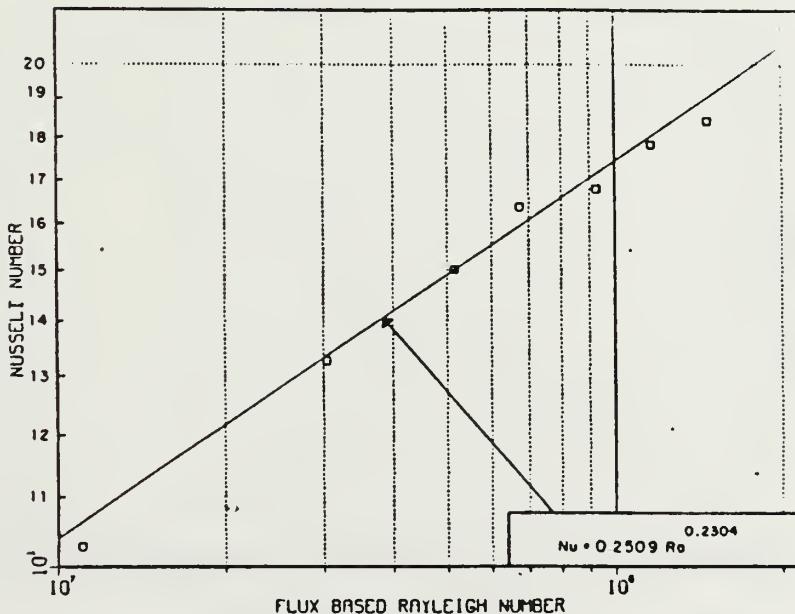


Figure 4.20 Flux Based Rayleigh Numbers, Chip 3

CHIP NUMBER 4

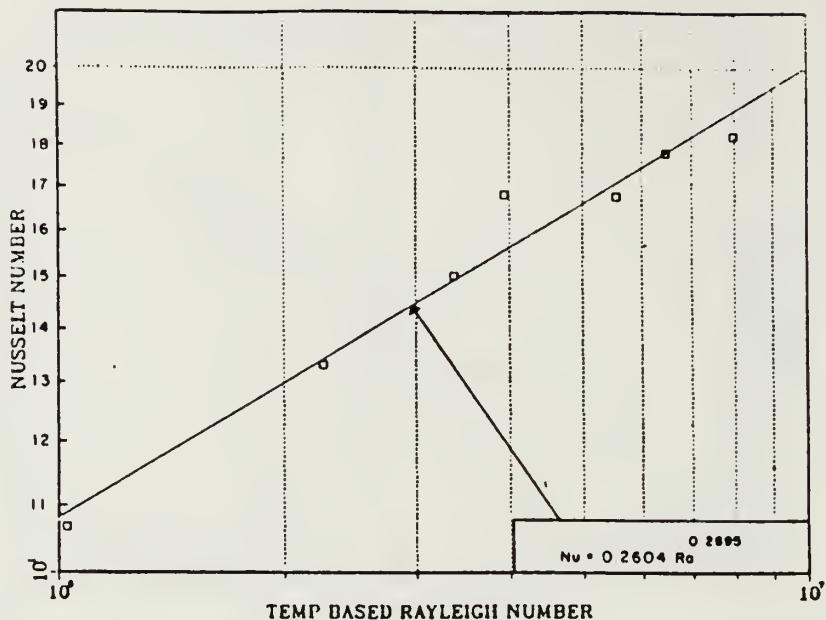


Figure 4.21 Temperature Based Rayleigh Numbers, Chip 4

CHIP NUMBER 4

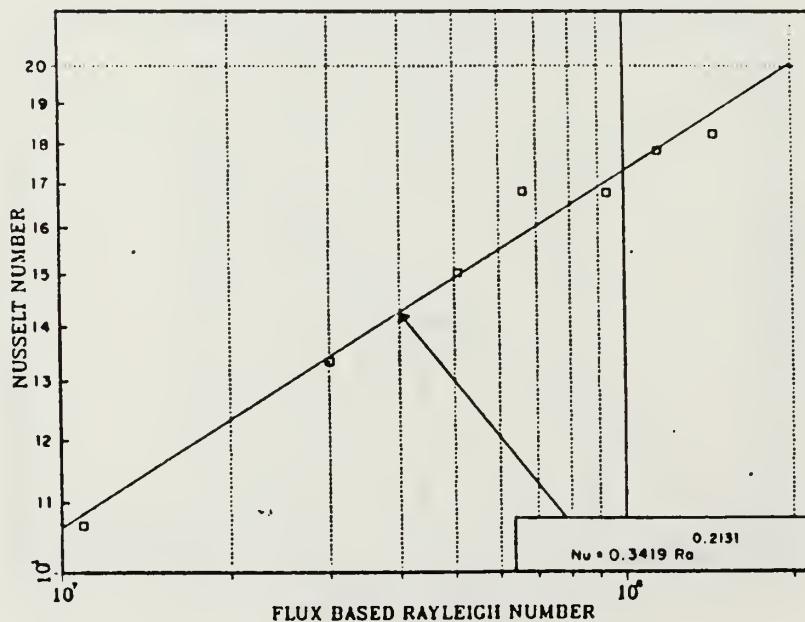


Figure 4.22 Flux Based Rayleigh Numbers, Chip 4

CHIP NUMBER 5

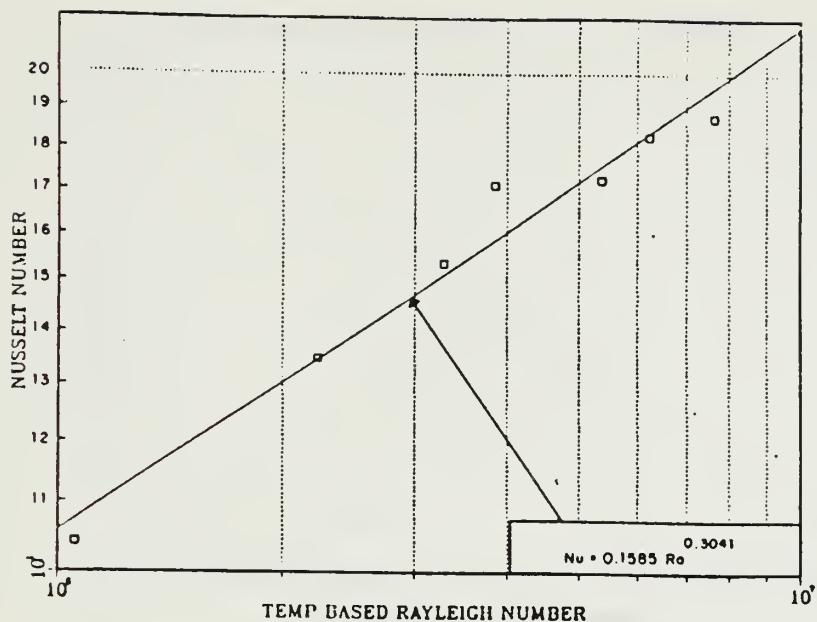


Figure 4.23 Temperature Based Rayleigh Numbers, Chip 5

CHIP NUMBER 5

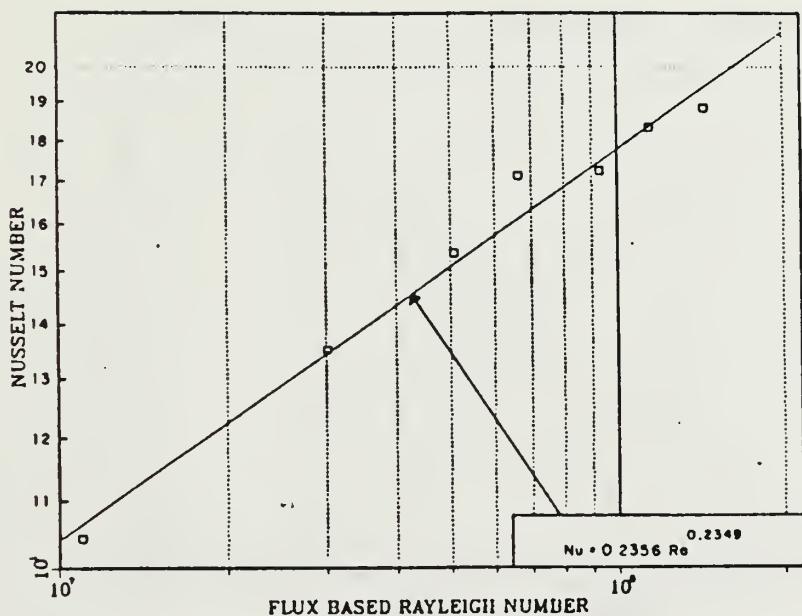


Figure 4.24 Flux Based Rayleigh Numbers, Chip 5

CHIP NUMBER 6

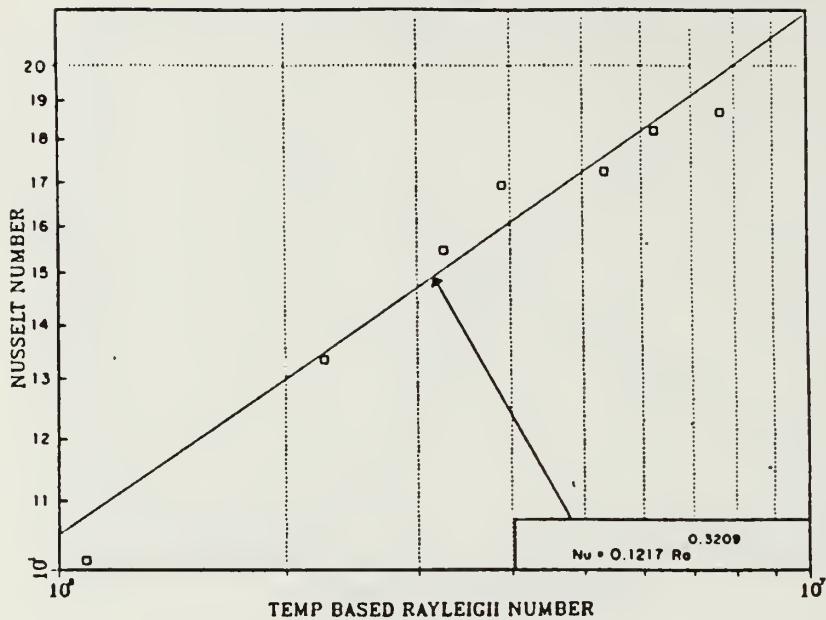


Figure 4.25 Temperature Based Rayleigh Numbers, Chip 6

CHIP NUMBER 6

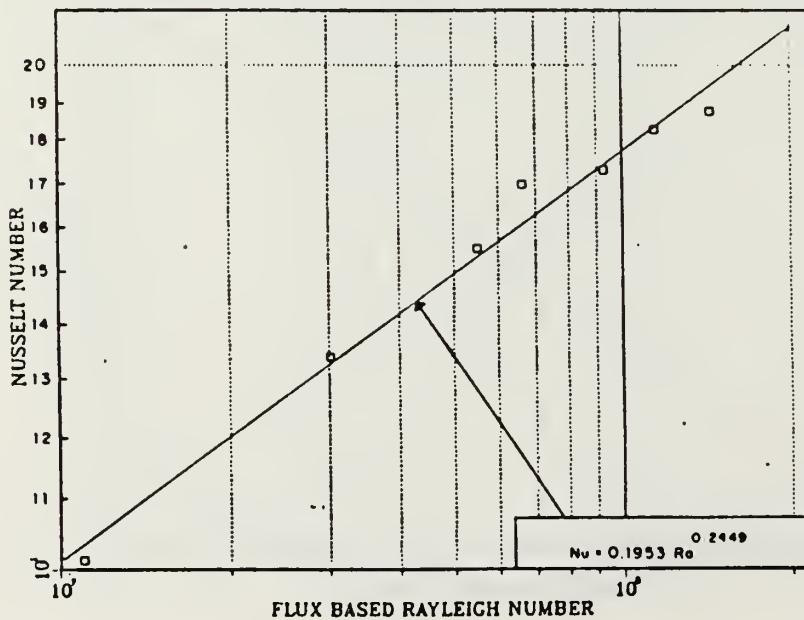


Figure 4.26 Flux Based Rayleigh Numbers, Chip 6

CHIP NUMBER 7

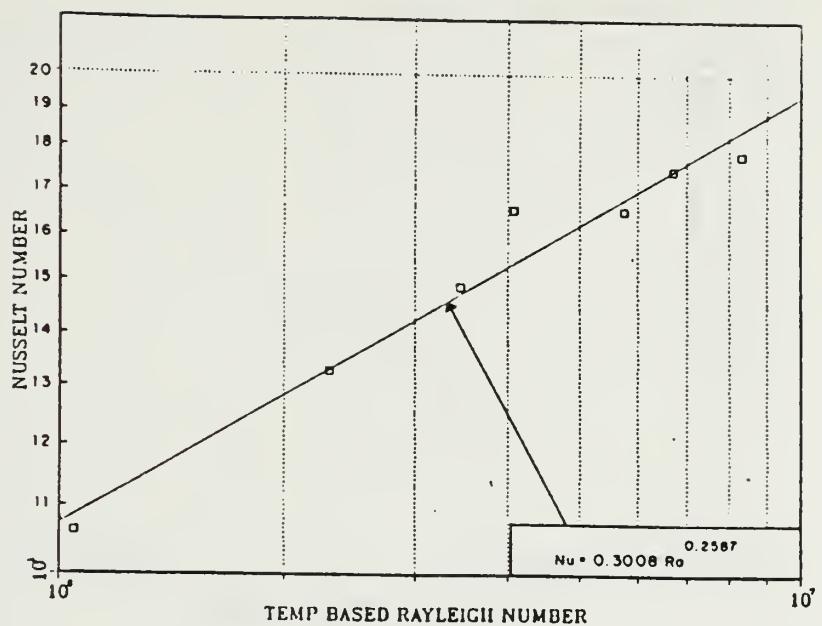


Figure 4.27 Temperature Based Rayleigh Numbers, Chip 7

CHIP NUMBER 7

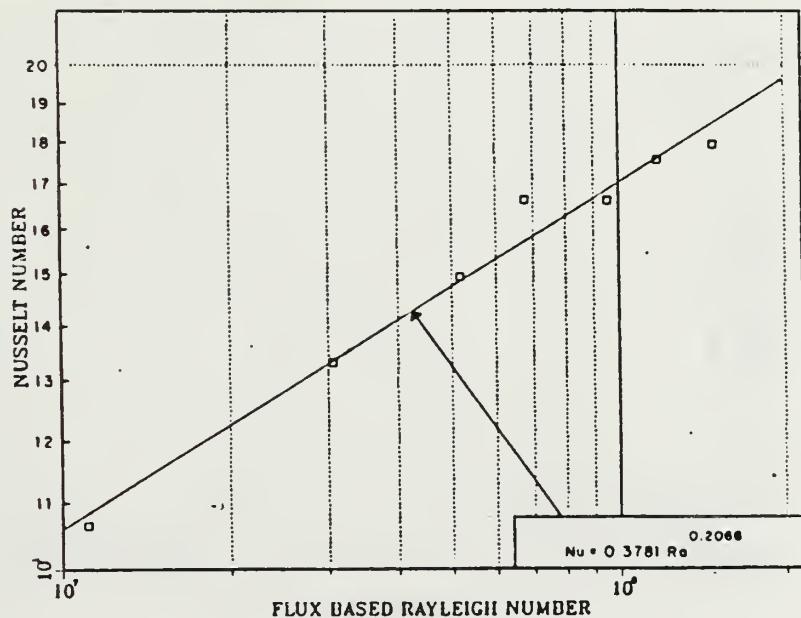


Figure 4.28 Flux Based Rayleigh Numbers, Chip 7

CHIP NUMBER 8

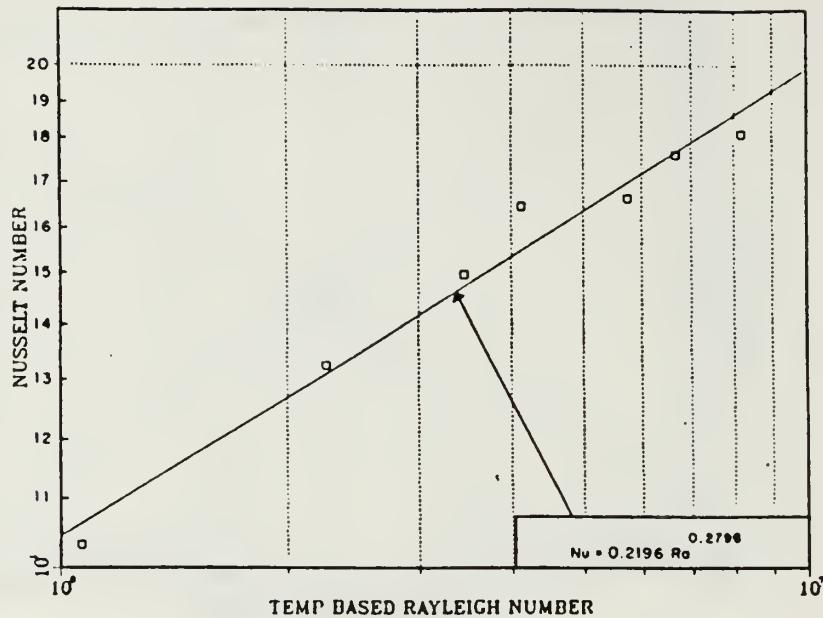


Figure 4.29 Temperature Based Rayleigh Numbers, Chip 8

CHIP NUMBER 8

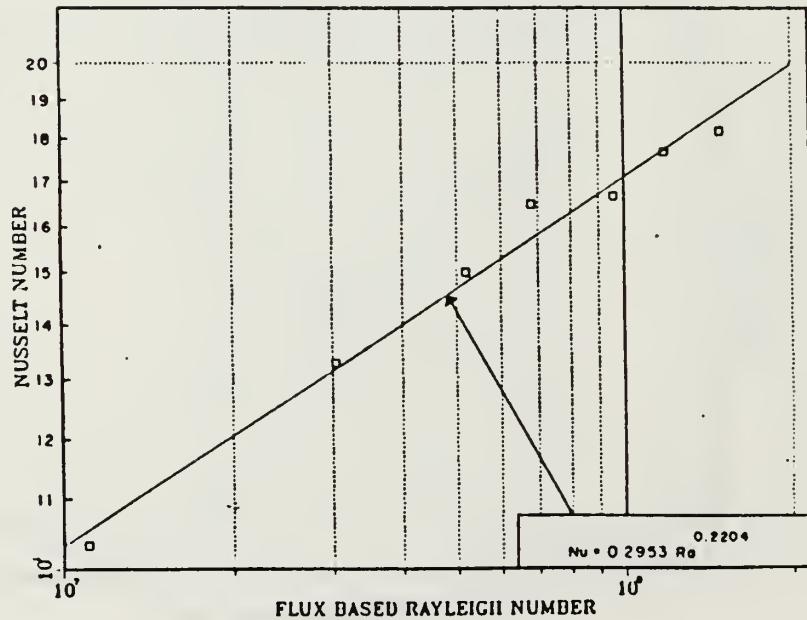


Figure 4.30 Flux Based Rayleigh Numbers, Chip 8

CHIP NUMBER 9

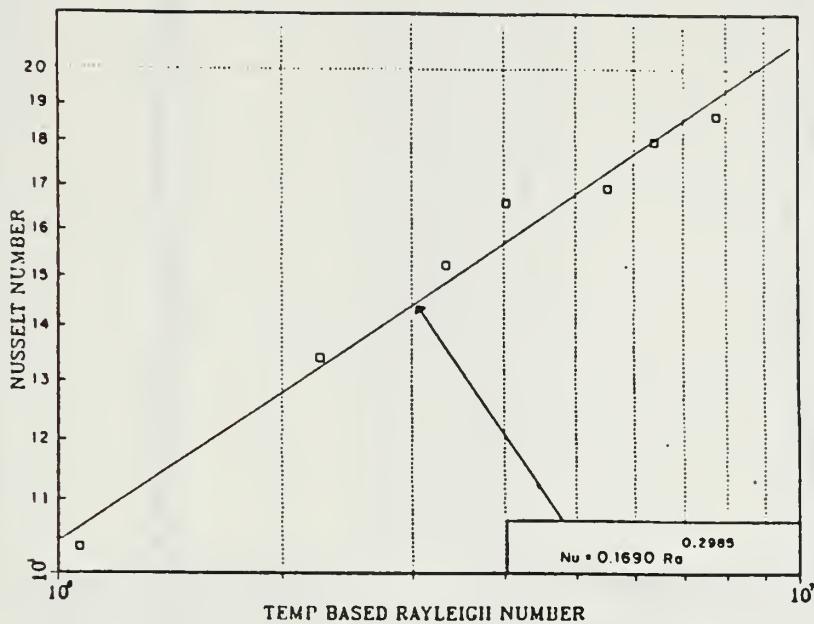


Figure 4.31 Temperature Based Rayleigh Numbers, Chip 9

CHIP NUMBER 9

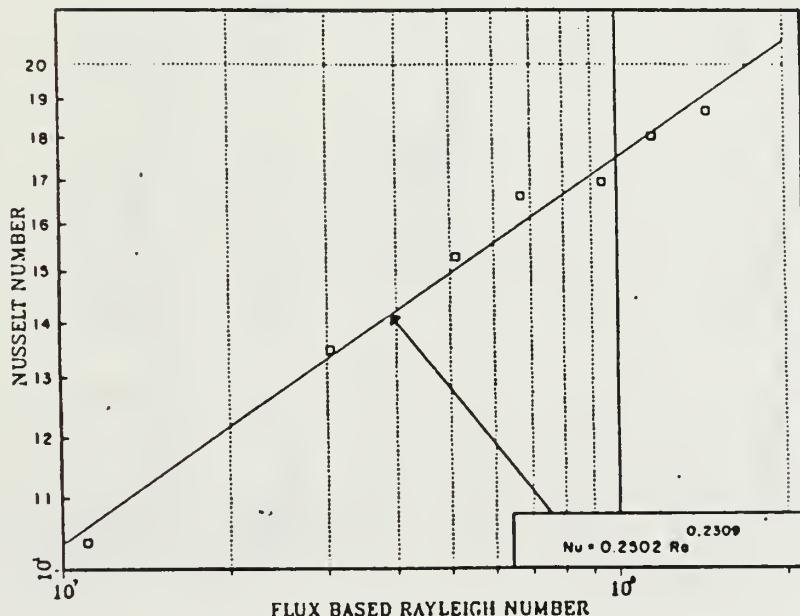


Figure 4.32 Flux Based Rayleigh Numbers, Chip 9

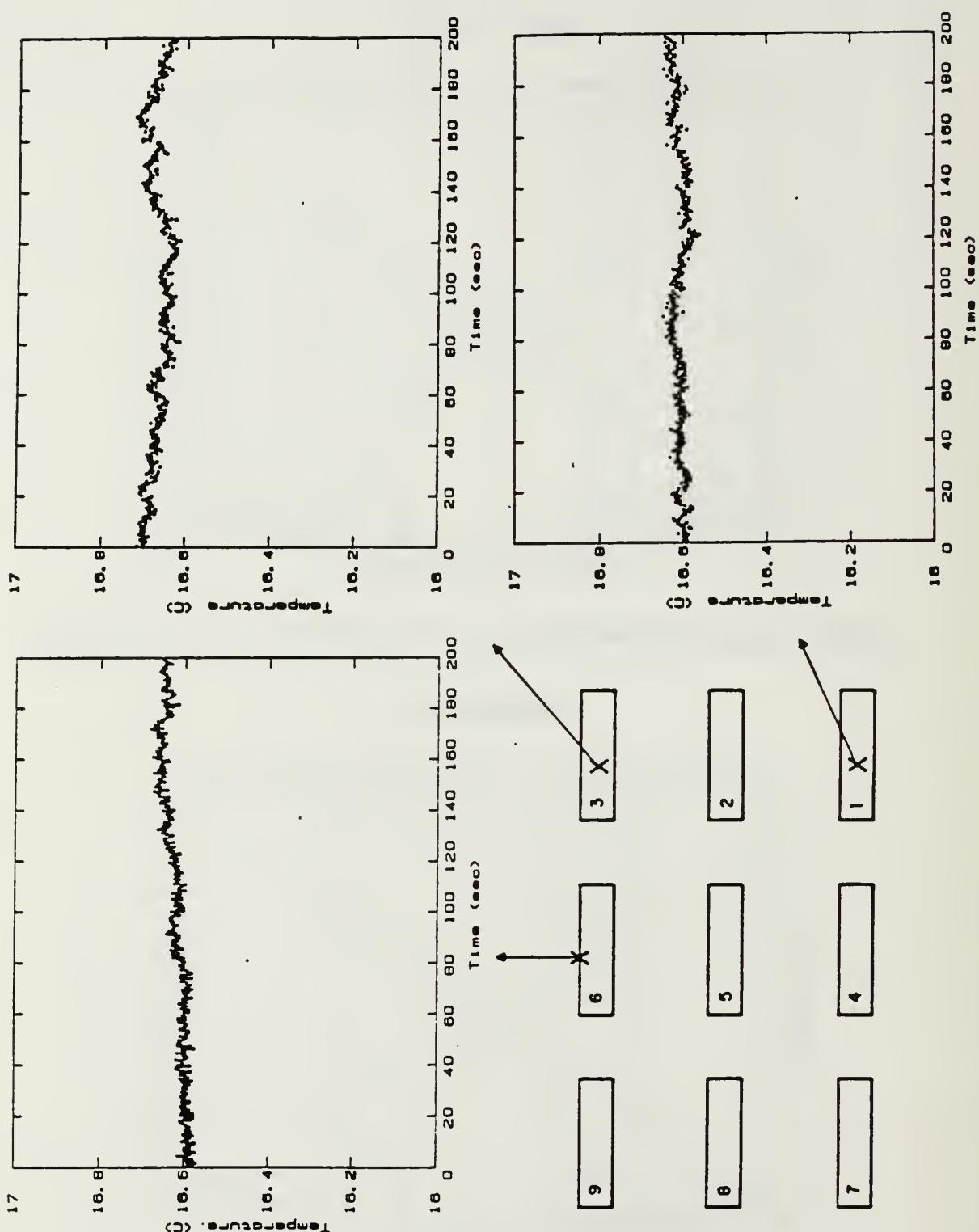


Figure 4.33 Temperature Variation for Input Power 0.3 W

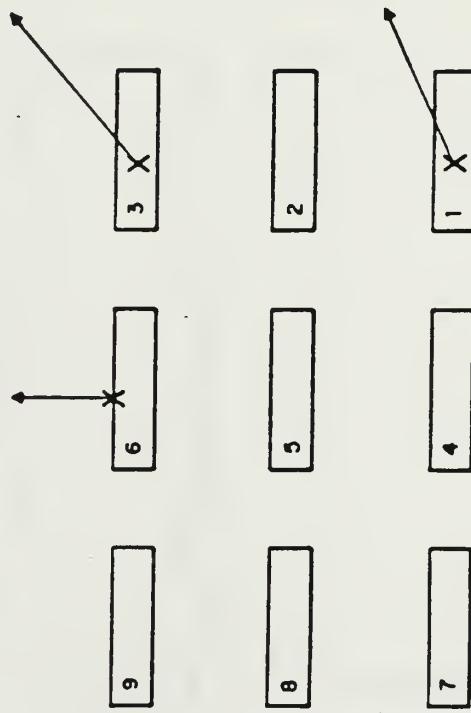
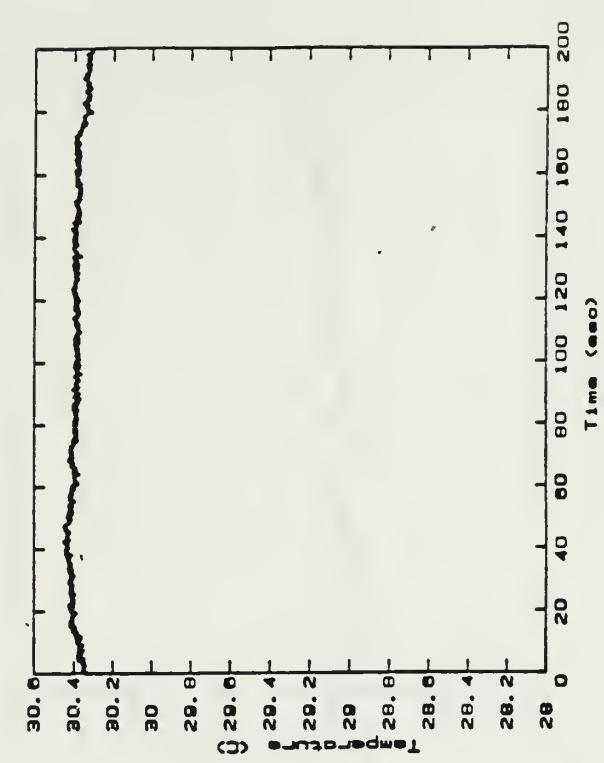
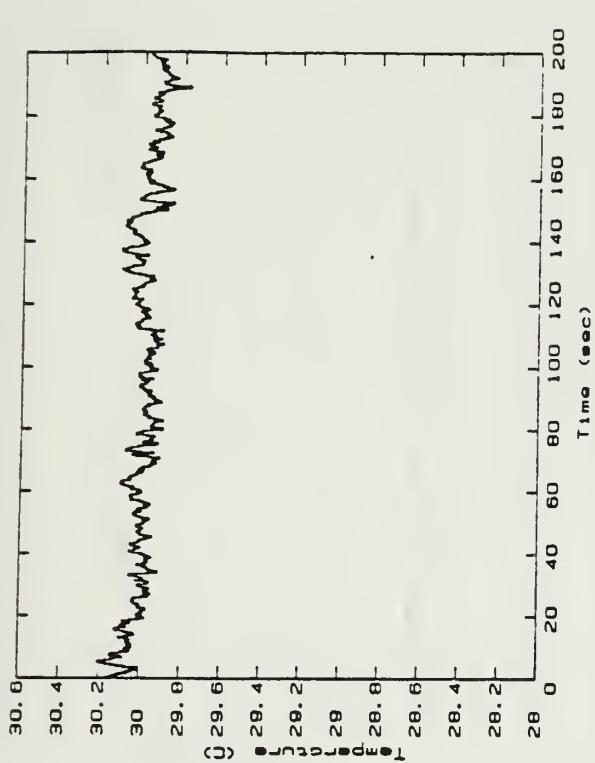
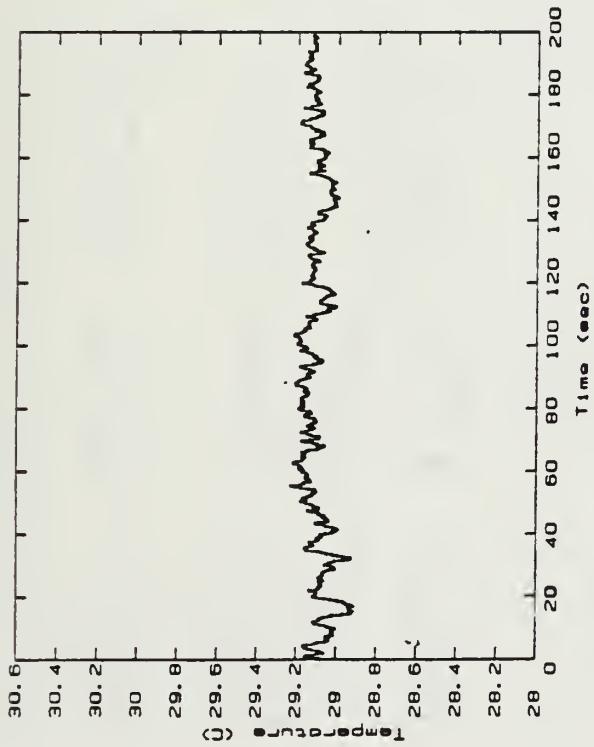


Figure 4.34 Temperature Variation for Input Power 0.7 W

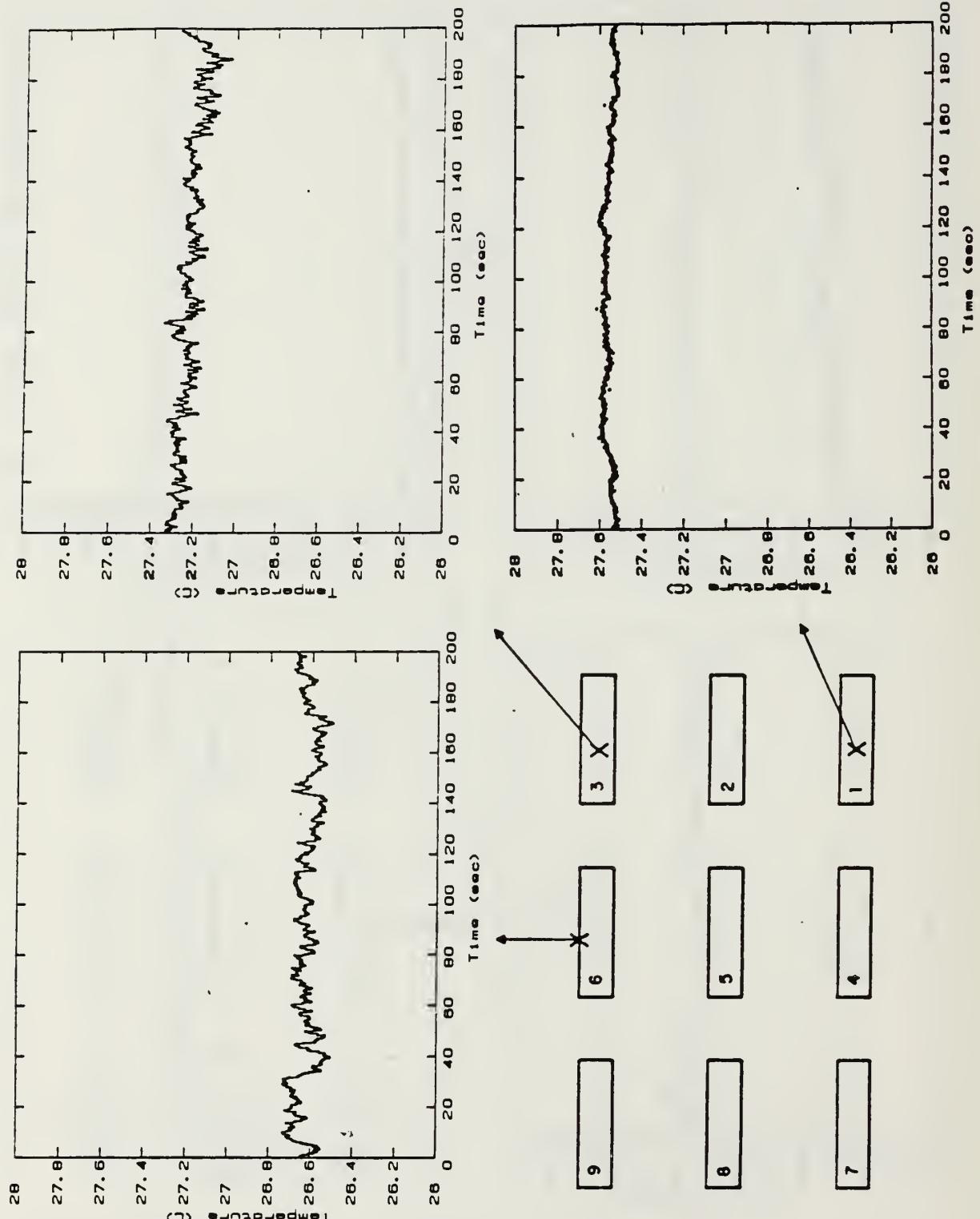


Figure 4.35 Temperature Variation for Input Power 1.1 W

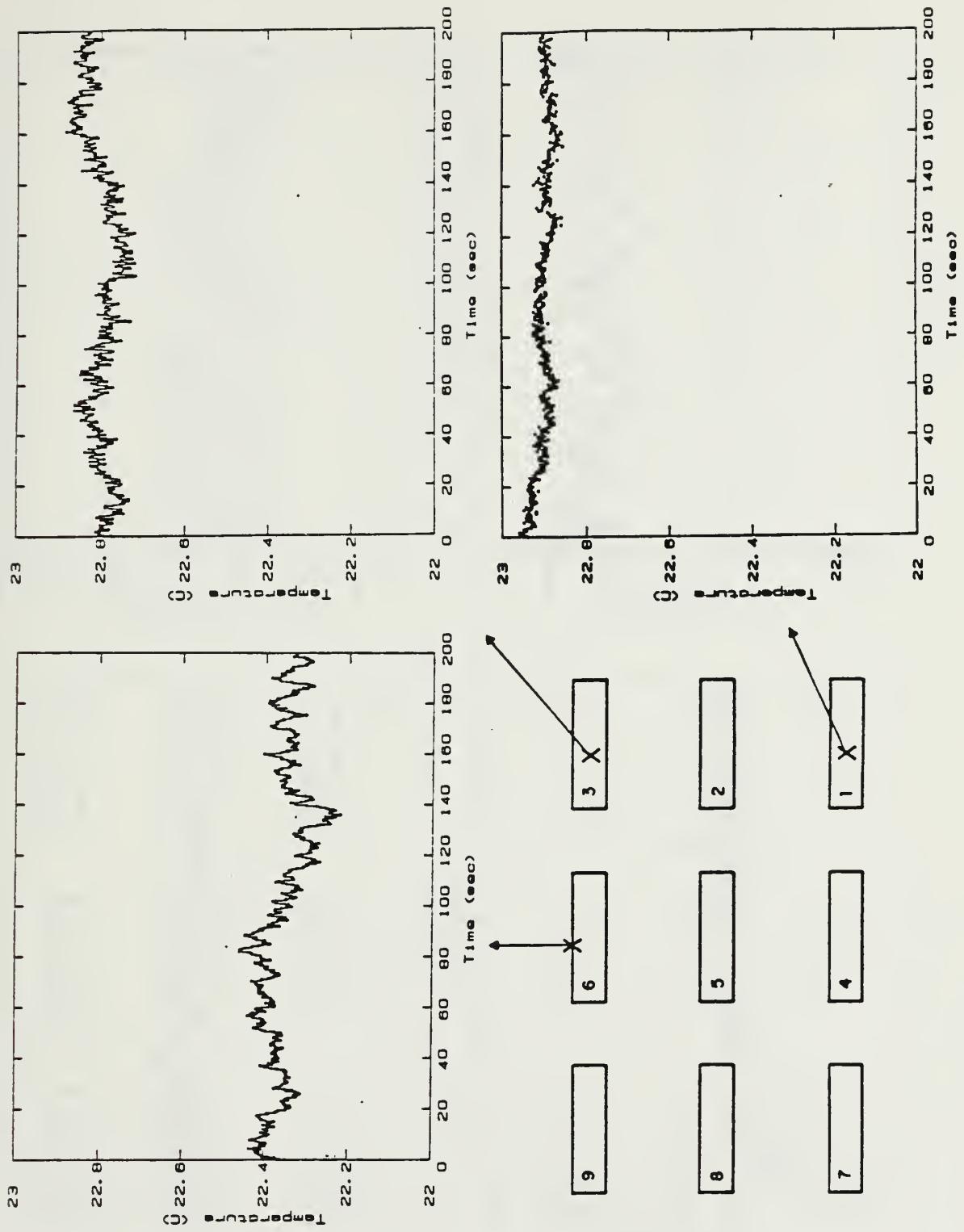


Figure 4.36 Temperature Variation for Input Power 1.5 W

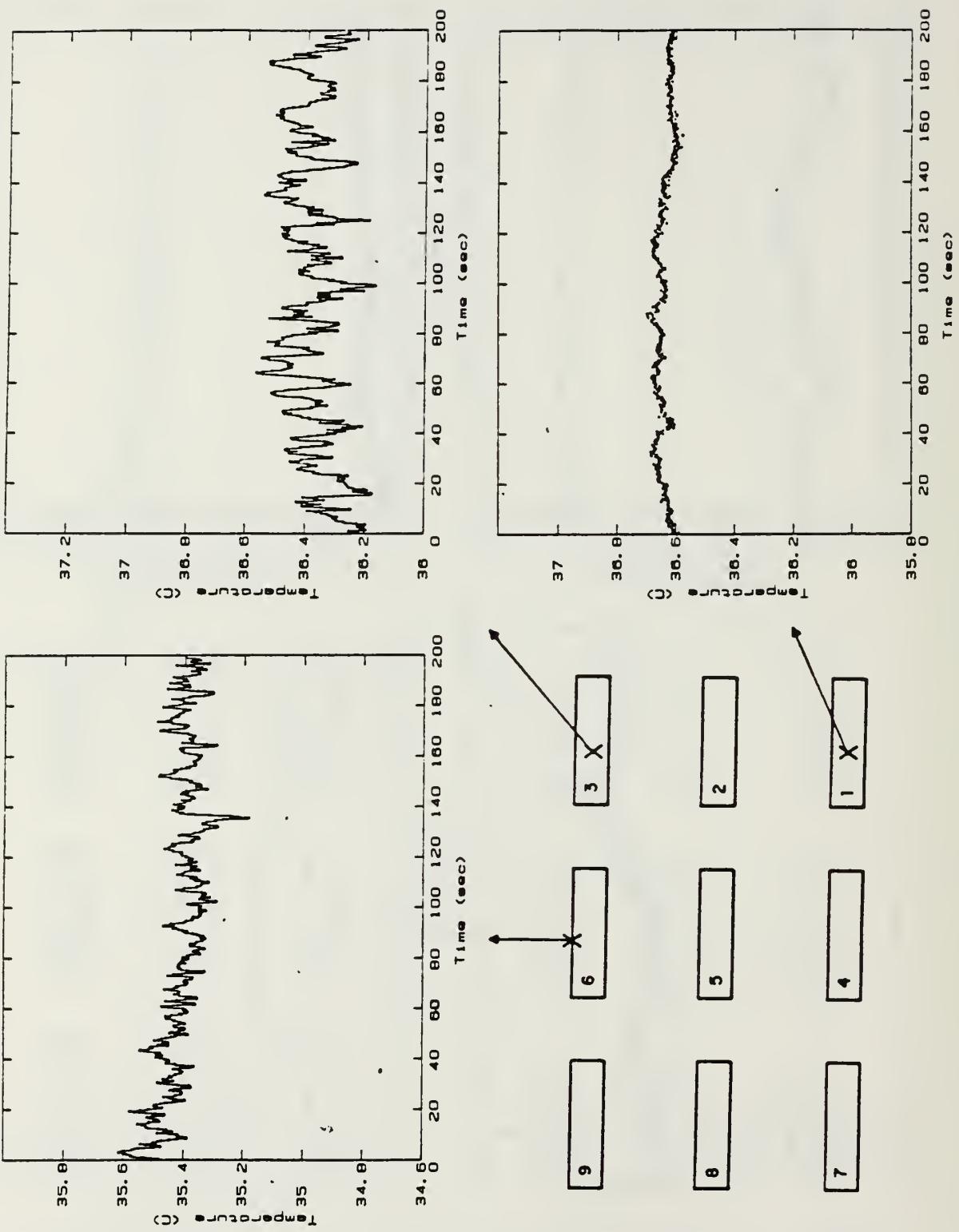


Figure 4.37 Temperature Variation for Input Power 1.9 W

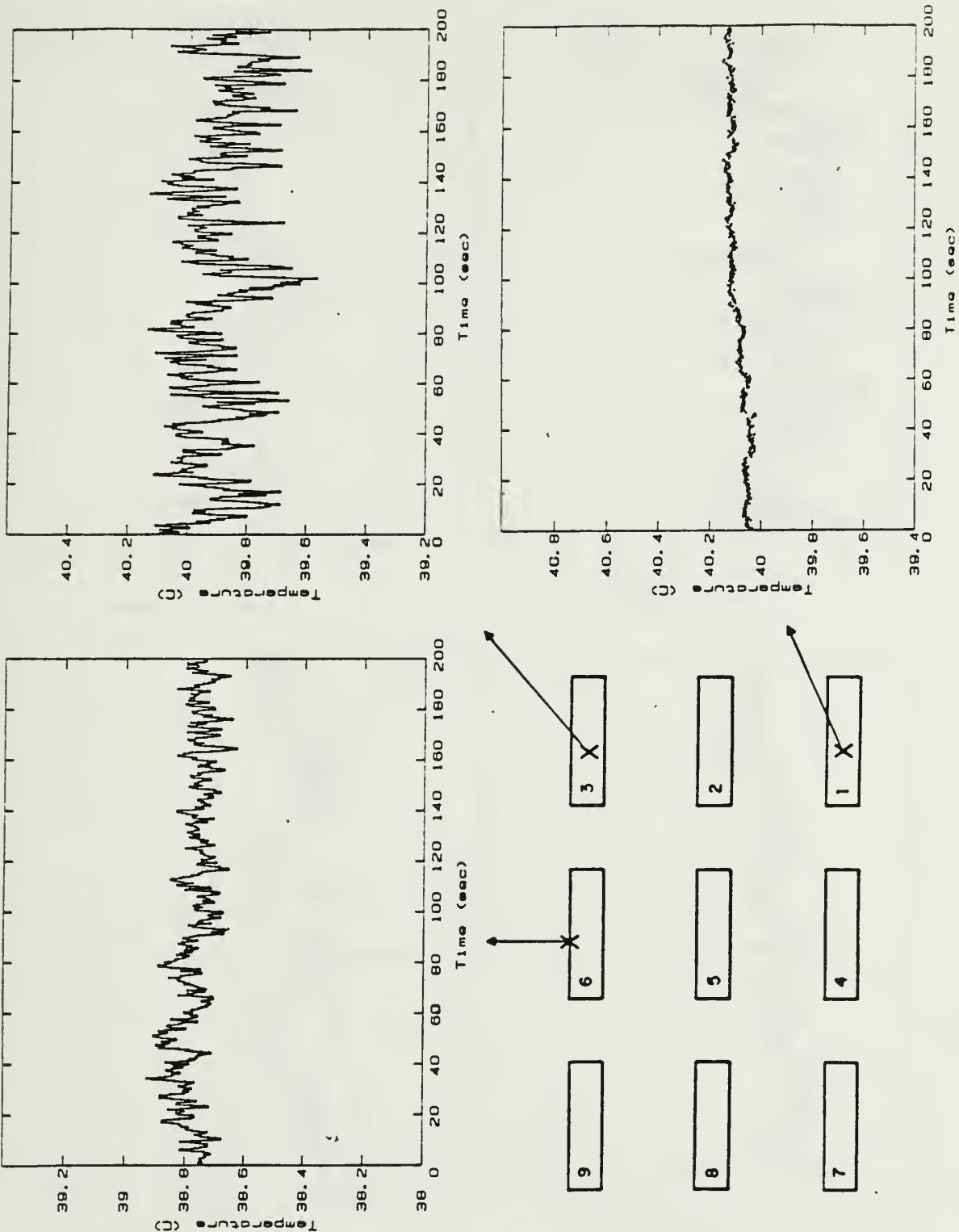


Figure 4.38 Temperature Variation for Input Power 2.3 W

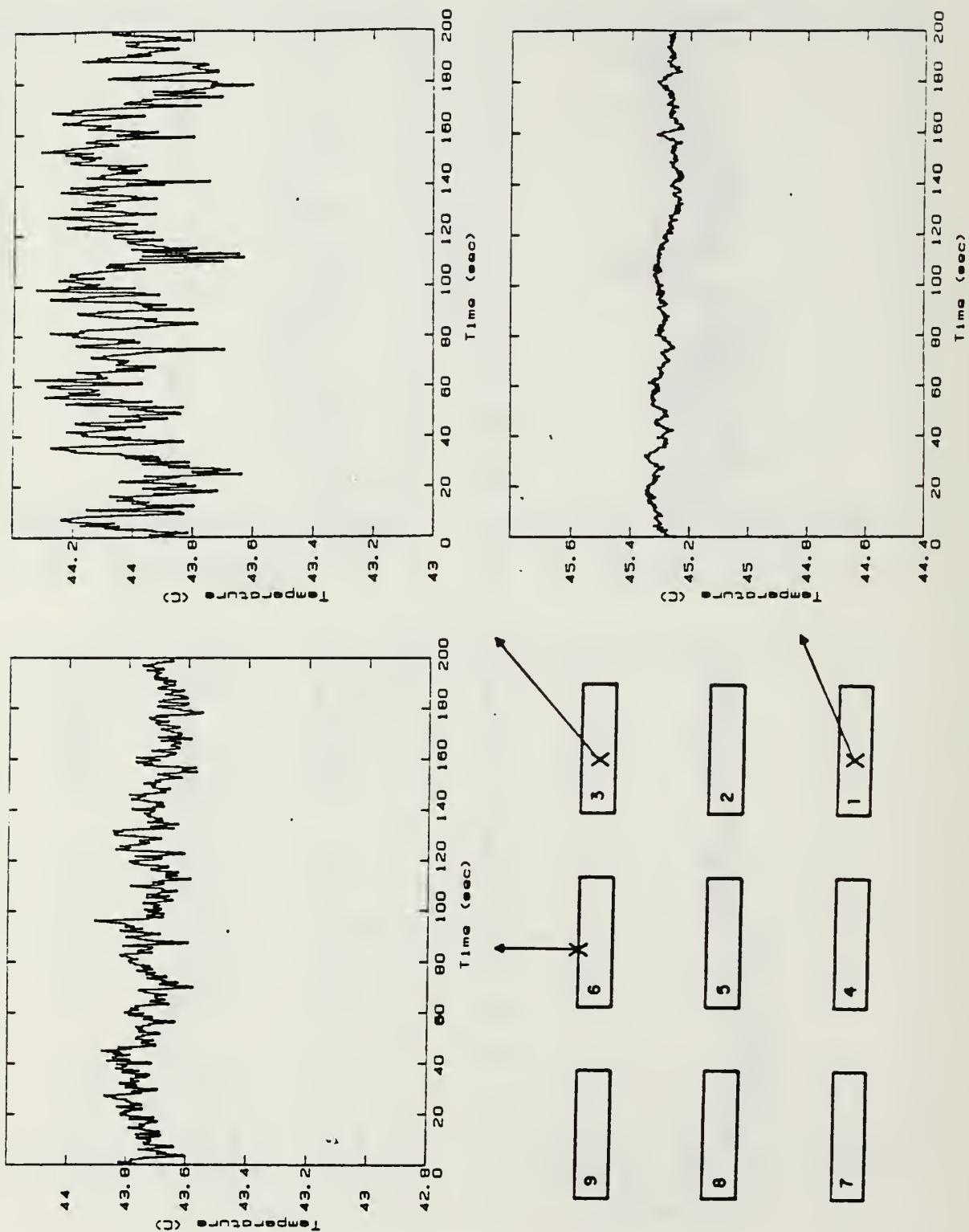


Figure 4.39 Temperature Variation for Input Power 2.7 W

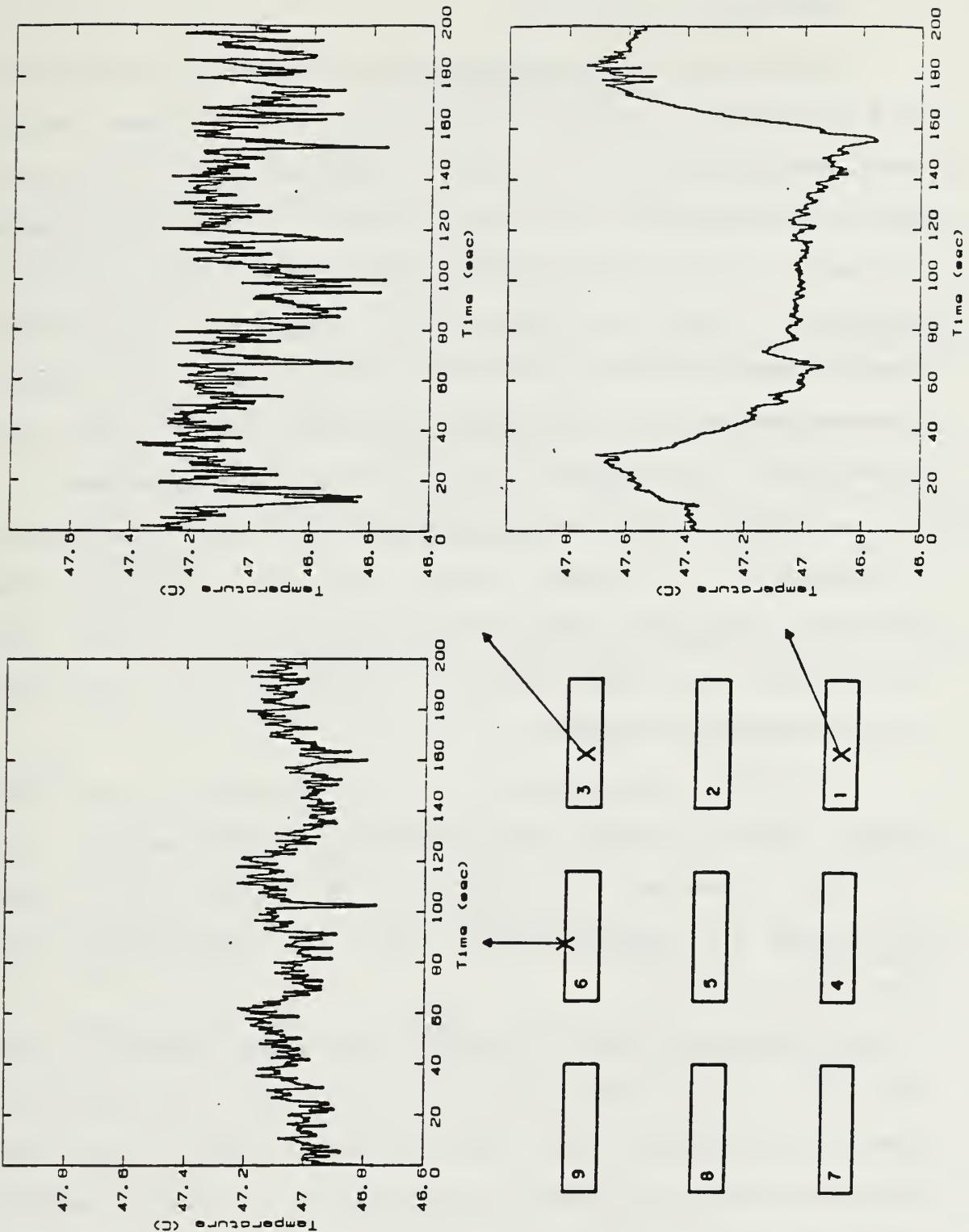


Figure 4.40 Temperature Variation for Input Power 3.1 W

C. TEMPERATURE VARIATIONS

The temperature variations with time were investigated and reported in Figures 4.33 through 4.40. These results were motivated by the studies conducted by Liu, Yang and Kelleher [Liu et al., 1987, pp. 486-97]. Three thermocouple channels, numbers 1, 13 and 32 were scanned individually at a rate of 3 times per second for a period of 200 seconds. These quantitative results were then plotted. The results clearly demonstrate a multiple frequency content signal for most of the power levels investigated in this experiment.

An observation of this experiment was that the output of thermocouple #1 remained steady with time throughout the increase in power levels. The temperature level for this thermocouple was also generally higher than for the other two thermocouples sampled.

A possible explanation for these results is that the cold, stagnant fluid layer created by the bottom heat exchanger prevented the penetration of warmer fluid below the bottom row of components. This is also supported by flow visualization.

One exception is at 3.1 watts. As seen in Figure 4.40, there is a large fluctuation of temperature with time. A possible explanation for this fluctuation may be that the increased energy acquired by the fluid at this power setting enabled the flow to force itself into the stagnant region at the bottom of the chamber.

V. RECOMMENDATIONS

There is a great deal more experimentation, to be accomplished with this component configuration. Three possible variations to the chamber are :

- Placing a spacer in the chamber to reduce the chamber width. This would act in the same manner as a shrouding wall and would affect the heat transfer characteristics.
- Setting the bottom heat exchanger to a temperature other than 10°C. The energy expended to maintain the bottom heat exchanger at 10°C is considerable. If reasonable components temperatures can be realized by maintaining the bottom heat exchanger at a higher temperature level then the energy consumption of the system would be reduced.
- Powering different configurations other than the entire array. This could possibly offer some explanation of the flow patterns observed in the chamber.

Other possible improvements to software and hardware are:

- Producing a plotting program that would read the data directly from the data acquisition unit for plots of Nusselt vs. Rayleigh number.
- Implementation of measurement devices that have greater sensitivity to minor fluctuations in temperature variation.
- Development of a program that will perform frequency analysis on the data recorded by the program Fastscan.

APPENDIX A

SAMPLE CALCULATIONS

Throughout this appendix, the sample calculations will be based on component number one with a power input of 0.71 watts.

1. Determination of Input Power

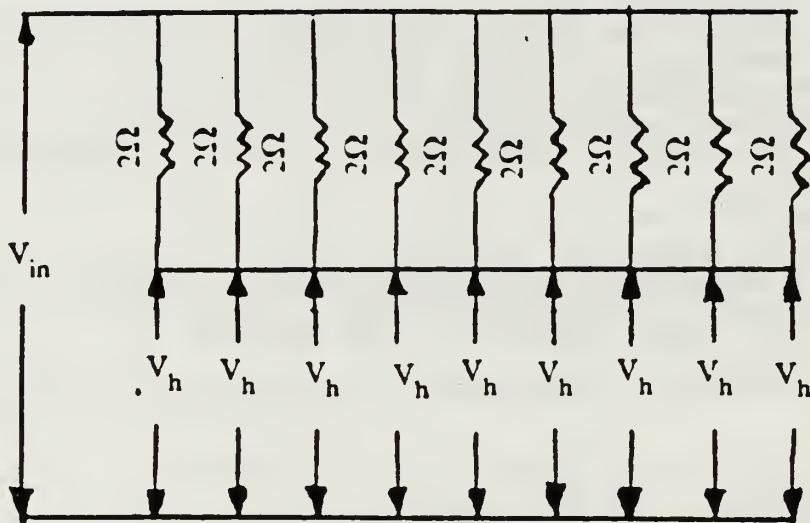


Figure A.1 Electrical Network of Power Input

From Equation (3.4):

$$Q_{in} = ((3.218 - 0.5278)(0.5278))/2$$

2. Estimation of Conduction Loss

Equation 3.3 requires T_s , T_b and R_{con} . T_s and T_b were read directly from thermocouples placed immediately behind the heaters and on the back of the board, respectively. R_{con} was calculated by using the constriction resistance formulas developed by Mikic and repeated in [Kraus and Bar-Cohen, 1983, pp. 76-9]. The conduction losses for components 3, 5 and 7 were then averaged to yield a total conduction loss.

3. Calculation of Nusselt and Rayleigh Numbers

The calculations of the convection coefficient from Equation (3.5) was:

$$Q_{net} = hA(T_{avg} - T_c)$$

$$\begin{aligned} h &= \frac{Q_{net}}{A(T_{avg} - T_c)} \\ &= \frac{.703}{(5.76 \times 10^{-4})(11.51)} \\ &= 106.04 \text{ W/m}^2 \text{ } ^\circ\text{K} \end{aligned}$$

From Equation (3.10):

$$\begin{aligned} T_{film} &= \frac{T_{avg} + T_c}{2} \\ &= \frac{21.51 + 10}{2} \end{aligned}$$

$$T_{film} = 15.75^{\circ}\text{C}$$

Using the relationships of [3-M Manual, 1985, pp. 9-60], the physical properties of FC-75 were:

$$k_f = (.65 - 7.8947 \times 10^{-4} * T_{film}) (0.1)$$
$$= 0.0637 \text{ W/m}^{\circ}\text{C}$$

$$\rho = 1000(1.825 - 0.00246 * T_{film})$$
$$= 1823.21 \text{ Kg/m}^3$$

$$c_p = 4180(.241111 + 3.7037 \times 10^{-4} * T_{film})$$
$$= 1032.23 \text{ J/Kg}^{\circ}\text{C}$$

$$v = 10^{-6}(1.4074 - 2.964 \times 10^{-2} * T_{film})$$
$$+ 3.8018 \times 10^{-4} * T_{film}$$
$$- 2.7308 \times 10^{-6} * T_{film}$$
$$+ 8.1679 \times 10^{-9} * T_{film})$$

$$v = 1.024 \times 10^{-6} \text{ m}^2/\text{sec}$$

$$\beta = \frac{.00246}{1.825 - .00246 * T_{film}}$$

$$\beta = 1.377 \times 10^{-3}$$

Then from Equation (3.1):

$$\begin{aligned} \text{Nu} &= \frac{hL}{K_f} \\ &= \frac{106.04 (.008)}{.0637} \\ &= 13.32 \end{aligned}$$

$$\begin{aligned} \alpha &= \frac{K}{\rho c_p} \\ &= \frac{.0637}{1823.2 * 1032.2} \\ &= 3.38 \times 10^{-8} \text{ m}^2/\text{sec} \end{aligned}$$

$$\text{Pr} = \frac{\nu}{\alpha}$$

$$\begin{aligned} &= \frac{1.024 \times 10^{-6}}{3.38 \times 10^{-8}} \\ &= 30.3 \end{aligned}$$

$$\begin{aligned} \text{Gr}_t &= \frac{g\beta L^3 (T_{avg} - T_c)}{\nu^2} \\ &= \frac{9.81 (1.377 \times 10^{-3}) (.008)^3 (11.51)}{(1.024 \times 10^{-6})^2} \\ &= 7.592 \times 10^4 \end{aligned}$$

From Equation (3.11), the temperature based Rayleigh number was:

$$Ra_t = Gr_t * Pr$$

$$= 2.3 \times 10^6$$

From Equation (3.12), the flux based Rayleigh number was:

$$Ra_f = 3.06 \times 10^7$$

APPENDIX B

UNCERTAINTY CALCULATIONS

Uncertainty calculations were evaluated using the root mean square formulation described in [Beckwith, Buck and Marangoni, 1982, pp. 261-292]. The following calculations are for components number one at 0.7 watts (see Table 4.10):

TABLE 16
UNCERTAINTIES IN VARIABLES

<u>Variables</u>	<u>Uncertainties</u>	<u>Reference</u>
L	10^{-5} m	Resolution
T	0.1 °C	Thermocouple readings
R _p	0.02	1% Variation
K _p	1.5 %	[Touloukian, 1986, p. 970]
V	0.001 V	Resolution

The uncertainty in the net power added to the fluid was:

$$\delta Q_{\text{net}} = (\delta \text{Power}^2 + \delta Q_{\text{loss}}^2)^{1/2}$$

where

$$\delta \text{Power} = 0.01 * \text{Power}$$

$$= .0071 \text{ W}$$

$$\begin{aligned}\delta Q_{\text{loss}} &= 0.055 * Q_{\text{loss}} \\ &= .000159 \text{ W}\end{aligned}$$

Therefore,

$$\delta Q_{\text{net}} = .0071$$

The uncertainty for the other variables used were:

$$\delta T_{\text{sink}} = \delta T$$

$$= 0.1 \text{ K}$$

$$\delta T_{\text{film}} = (\delta T_{\text{sink}}^2 + \delta T_{\text{avg}}^2)^{1/2}$$

$$= (.01^2 + 0.1^2)^{1/2}$$

$$= .1414 \text{ K}$$

$$\delta T_{\Delta t} = (\delta T_{\text{avg}}^2 + \delta T_{\text{sink}}^2)^{1/2}$$

$$= (0.1^2 + .01^2)^{1/2}$$

$$= .1414 \text{ K}$$

$$\frac{\delta h}{h} = \left[\left(\frac{\delta Q_{net}}{Q_{net}} \right)^2 + \left(\frac{\delta T_{Delt}}{T_{Delt}} \right)^2 \right]^{1/2}$$

$$= \left[\left(\frac{.0071}{.703} \right)^2 + \left(\frac{.1414}{11.51} \right)^2 \right]^{1/2}$$

$$= .0159$$

$$\frac{\delta Nu}{Nu} = \frac{\delta h}{h}$$

$$= .0159$$

$$\frac{\delta Gr_t}{Gr_t} = \frac{\delta T_{Delt}}{T_{Delt}}$$

$$= \frac{.1414}{11.51}$$

$$= .0123$$

$$\frac{\delta Ra_t}{Ra_t} = \frac{\delta Gr_t}{Gr_t}$$

$$= .0123$$

$$\frac{\delta \text{Ra}_f}{\text{Ra}_f} = \frac{\delta Q_{\text{net}}}{Q_{\text{net}}}$$

$$= \frac{.0071}{.703}$$

$$= .0101$$

APPENDIX C

SOFTWARE

1. Acquire

```
10 ! FILE ACQUIRE
20 !
30 ! EDITED BY LT T J BENEDICT, USN
40 !
41 ! READ FILE "READ_ME"
42 !
50 COM /Co/ D(7)
60 DIM Emf(76),Power(9),T(76)
70 !
80 !CORRELATION FACTORS TO CONVERT EMF TO DEGREES CELCIUS
90 DATA 0.10086091,25727.9,-767345.8,78025596,
100 DATA -9247486589.6,98E11,-2.66E13,3.94E14
110 !
120 READ D(*)
130 Rp=2.000
140 PRINTER IS 701
150 BEEP
160 !
170 INPUT "ENTER THE INPUT MODE: 0-SYS, 1-FILE",Im
180 !
190 IF Im=1 THEN
200 BEEP
210 INPUT "ENTER THE NAME OF THE FILE TO BE READ",Oldfile$ 
211 !
220 PRINT USING "15X,,"THESE RESULTS ARE STORED IN FILE : "",10A":Oldfile$ 
230 !
240 ELSE
250 BEEP
260 INPUT "ENTER THE NAME OF THE NEW FILE",Newfile$ 
261 PRINT USING "10X,,"THESE RESULTS ARE STORED IN FILE: "",10A":Newfile$ 
270 END IF
280 PRINT
290 PRINT
291 !
300 INPUT "ENTER THE AMBIANT TEMP",Temp$
310 PRINT USING "15X,,"AMBIENT TEMP WAS: "",10A":Temp$ 
320 !
330 INPUT "FLOW VIZ? Y/N",Ans$
340 INPUT "VOLTMETER READING",VS
350 PRINT USING "15X,,"VOLTMETER READING WAS: "",10A":VS
360 !
370 INPUT "ENTER THE BATH TEMP",BS
380 PRINT USING "15X,,"BATH TEMP WAS : "",10A":BS
390 !
400 IF Ans$="Y" THEN PRINT USING "15X,,"THIS RUN WAS RECORDED WITH FLOW VIZ".
40A"!
410 !
420 IF Im=1 THEN ASSIGN @File TO Oldfile$ 
430 PRINT
440 !
450 IF Im=0 THEN
460 CREATE BDAT Newfile$,5
470 ASSIGN @File TO Newfile$ 
480 END IF
490 !
500 ! READ DATA
510 !
520 IF Im=0 THEN
530 OUTPUT 709;"AR AF00 AL79"
```

```

540  OUTPUT 722;"F1 R1 T1 Z0 FLO"
550  !
560  FOR I=0 TO 76
570  OUTPUT 709;"AS"
580  WAIT 1
590  ENTER 722;Emf(I)
600  BEEP
610  NEXT I
620  !
630  OUTPUT @FILE;Emf(*)
640  !
650  ELSE
660  ENTER @FILE;Emf(*)
670  END IF
680  !
690  OUTPUT 709;"TD"
700  !
710  FOR I=0 TO 60
720  Sum=0
730  FOR J=1 TO 7
740  Sum=Sum+D(J)*Emf(I)*J
750  NEXT J
760  T(I)=Sum
770  NEXT I
780  !
790  FOR I=71 TO 76
800  Sum=0
810  FOR J=1 TO 7
820  Sum=Sum+D(J)*Emf(I)*J
830  NEXT J
840  T(I)=Sum
850  NEXT I
860  !
870  ! POWER CALCULATIONS
880  !
890  J=1
900  Volt=Emf(61)
910  !
920  FOR I=62 TO 70
930  Power(J)=Emf(I)*(Volt-Emf(I))/Rp
940  J=J+1
950  NEXT I
960  !
970  BEEP
980  BEEP
990  PRINT USING "14X,;"ALL TEMPERATURES ARE IN DEGREES CELCIUS"""
1000 !
1010  PRINT      ..
1020 !
1030  PRINT USING "12X,;"CENTER      TOP      RIGHT      LEFT      BOTTOM
BACK"""
1040  PRINT
1050  PRINT USING "1X,;"CHIP NO1: "",5(ZZ.DDE.2X).2X.ZZ.DDE":T(0),T(1),T(2),T(
.T(4),T(5)
1060  PRINT USING "5X,;"POWER (WATTS): "",ZZ.DDE":Power(1)
1061  PRINT
1070  PRINT USING "1X,;"CHIP NO2: "",5(ZZ.DDE.2X).2X.ZZ.DDE":T(6),T(7),T(8),T(
.T(10),T(11)
1080  PRINT USING "5X,;"POWER (WATTS): "",ZZ.DDE":Power(2)
1081  PRINT

```

```

1090 PRINT USING "1X,."CHIP NO3: "",5(ZZ.DDE.2X),2X,ZZ.DDE";T(12),T(13),T(14)
1100 PRINT USING "5X,."POWER (WATTS): "",ZZ.DDE":Power(3)
1101 PRINT
1110 PRINT USING "1X,."CHIP NO4: "",5(ZZ.DDE.2X),2X,ZZ.DDE";T(18),T(19),T(20)
1111 .T(22),T(23)
1120 PRINT USING "5X,."POWER (WATTS): "",ZZ.DDE":Power(4)
1121 PRINT
1130 PRINT USING "1X,."CHIP NO5: "",5(ZZ.DDE.2X),2X,ZZ.DDE";T(24),T(25),T(26)
1131 .T(27),T(28),T(29)
1140 PRINT USING "5X,."POWER (WATTS): "",ZZ.DDE":Power(5)
1141 PRINT
1150 PRINT USING "1X,."CHIP NO6: "",5(ZZ.DDE.2X),2X,ZZ.DDE";T(30),T(31),T(32)
1151 .T(33),T(34),T(35)
1160 PRINT USING "5X,."POWER (WATTS): "",ZZ.DDE":Power(6)
1161 PRINT
1170 PRINT USING "1X,."CHIP NO7: "",5(ZZ.DDE.2X),2X,ZZ.DDE";T(36),T(37),T(38)
1171 .T(39),T(40),T(41)
1180 PRINT USING "5X,."POWER (WATTS): "",ZZ.DDE":Power(7)
1181 PRINT
1190 PRINT USING "1X,."CHIP NO8: "",5(ZZ.DDE.2X),2X,ZZ.DDE";T(42),T(43),T(44)
1191 .T(45),T(46),T(47)
1200 PRINT USING "5X,."POWER (WATTS): "",ZZ.DDE":Power(8)
1201 PRINT
1210 PRINT USING "1X,."CHIP NO9: "",5(ZZ.DDE.2X),2X,ZZ.DDE";T(48),T(49),T(50)
1211 .T(51),T(52),T(53)
1220 PRINT USING "5X,."POWER (WATTS): "",ZZ.DDE":Power(9)
1230 !
1240 PRINT
1250 PRINT
1260 !
1270 PRINT USING "5X,."HEAT EXCHANGERS TEMPERATURES: RIGHT LEFT ***
1280 PRINT USING "10X,."BOTTOM:"",21X,2(ZZ.DDE.2X)":T(58),T(57)
1290 PRINT USING "10X,."TOP:"",24X,2(ZZ.DDE.2X)":T(60),T(59)
1300 PRINT
1310 PRINT
1320 !
1330 PRINT USING "5X,."BACK PLANE TEMPERATURES ARE :"""
1340 PRINT
1350 PRINT USING "10X,."T(55):"".2X,(ZZ.DDE.2X)":T(54)
1360 PRINT USING "10X,."T(56):"".2X,(ZZ.DDE.2X)":T(55)
1370 PRINT USING "10X,."T(57):"".2X,(ZZ.DDE.2X)":T(56)
1380 PRINT USING "10X,."T(72):"".2X,(ZZ.DDE.2X)":T(71)
1390 PRINT USING "10X,."T(73):"".2X,(ZZ.DDE.2X)":T(72)
1400 PRINT USING "10X,."T(74):"".2X,(ZZ.DDE.2X)":T(73)
1410 PRINT USING "10X,."T(75):"".2X,(ZZ.DDE.2X)":T(74)
1420 PRINT USING "10X,."T(76):"".2X,(ZZ.DDE.2X)":T(75)
1430 PRINT USING "10X,."T(77):"".2X,(ZZ.DDE.2X)":T(76)
1440 BEEP
1450 PRINTER IS 1
1460 !
1470 ASSIGN @FILE TO *
1480 END

```

2. CalcDiel

```
10 ! FILE NAME : CalcDiel
20 !
30 ! EDITED BY : Lt. T BENEDICT, USN
40
50 ! THIS PROGRAM ANALYSES THE DATA READ FROM
60 ! A DATA FILE DESINATED BY THE OPERATOR. IT
70 ! REDUCES THE DATA TO CALCUALTIONS OF NET
80 ! POWER, RAYLEIGH NUMBER AND NUSELT NUMBER.
90 !
100 COM /Co/ D(7)
110 !
120 DIM Emf(70),Power(9),T(60),Tavg(9),Ts(9)
130 DIM Tfilm(9),Qnet(9),H(9),K(9),Rho(9),Cp(9)
140 DIM N(9),Nu(9),Ra(9),Delt(9),Alfa(9),Pr(9)
150 DIM Gr(9),Beta(9),Dpow(9),Dts(9)
160 !
170 ! CORRLEATION FACTORS TO CONVERT Emf TO REGREES CELCIUS.
180 DATA 0.10086091,25727.9,-767345.8,78025596,
190 DATA -9247486589.6,98E11,-2.66E13.3.94E14
200 !
210 READ D(*)
220 !
230 ! RESISTANCE OF THE PRECISION RESISTOR IS: 1%
240 Rp=2.00
250 !
260 PRINTER IS 701
270 BEEP
280 BEEP
290 !
300 INPUT "ENTER THE NAME OF THE FILE CONTAINING DATA",Oldfile$
310 PRINT USING "15X,""THE RAW Emf DATA ARE FROM THE FILE:    "",10A";Oldfile$"
320 INPUT "ENTER THE POWER SETTING ",Power$
340 PRINT USING "17X,"" THE POWER SETTING PER CHIP WAS:    "",10A";Power$"
350 PRINT
370 !
380 BEEP
390 BEEP
400 ASSIGN @File TO Oldfile$
410 ENTER @File;Emf(*)
420 !
430 ! CONVERT Emf TO DEGREES CELCIUS
440 FOR I=0 TO 60
450 Sum=0
460 FOR J=0 TO 7
470 Sum=Sum+D(J)*Emf(I)*J
480 NEXT J
490 T(I)=Sum
500 NEXT I
510 !
520 ! CONVERT Emf TO POWER
530 J=1
540 Volt=Emf(61)
550 FOR I=62 TO 70
560 Power(J)=Emf(I)*(Volt-Emf(I))/Rp
570 Dpow(J)=.01*Power(J)
580 J=J+1
590 NEXT I
600 !
610 ! AREA OF THE BLOCK FACES
620 Acen=1.92E-4
```

```

530 Alef=1.44E-4
540 Arig=1.44E-4
550 Atop=4.8E-5
560 Abot=4.8E-5
570 Atot=5.76E-4
580 !
590 !CALCULATE THE AVERAGE TEMPERATURES OF THE BLOCK FACES
600 !
610 Tavg(1)=(T(0)*Acen+T(1)*Atop+T(2)*Arig+T(3)*Alef+T(4)*Abot)/Atot
620 Tavg(2)=(T(6)*Acen+T(7)*Atop+T(8)*Arig+T(9)*Alef+T(10)*Abot)/Atot
630 Tavg(3)=(T(12)*Acen+T(13)*Atop+T(14)*Arig+T(15)*Alef+T(16)*Abot)/Atot
640 Tavg(4)=(T(18)*Acen+T(19)*Atop+T(20)*Arig+T(21)*Alef+T(22)*Abot)/Atot
650 Tavg(5)=(T(24)*Acen+T(25)*Atop+T(26)*Arig+T(27)*Alef+T(28)*Abot)/Atot
660 Tavg(6)=(T(30)*Acen+T(31)*Atop+T(32)*Arig+T(33)*Alef+T(34)*Abot)/Atot
670 Tavg(7)=(T(36)*Acen+T(37)*Atop+T(38)*Arig+T(39)*Alef+T(40)*Abot)/Atot
680 Tavg(8)=(T(42)*Acen+T(43)*Atop+T(44)*Arig+T(45)*Alef+T(46)*Abot)/Atot
690 Tavg(9)=(T(48)*Acen+T(49)*Atop+T(50)*Arig+T(51)*Alef+T(52)*Abot)/Atot
700 !
710 ! UNCERTAINTY OF THE THERMOCOUPLE READINGS
720 Dt=.1
730 Dtavg=.1
740 !
750 ! RESISTANCE OF PLEXIGLASS AND UNCERTAINTY
760 Rc=764.65
770 !
780 ! CHIP BACK SURFACE TEMPERATURES
790 Ts(1)=T(5)
800 Ts(2)=T(11)
810 Ts(3)=T(17)
820 Ts(4)=T(23)
830 Ts(5)=T(29)
840 Ts(6)=T(35)
850 Ts(7)=T(41)
860 Ts(8)=T(47)
870 Ts(9)=T(53)
880 Tssum=0
890 FOR J=1 TO 9
900 Tssum=Tssum+Ts(J)
910 NEXT J
920 !
930 Tsavg=Tssum/9
940 !
950 ! CONDUCTION LOSS CALCULATION AND UNCERTAINTY
960 Qloss3=(T(17)-T(56))/Rc
970 Qloss5=(T(29)-T(55))/Rc
980 Qloss7=(T(41)-T(54))/Rc
990 Qloss=(Qloss3+Qloss5+Qloss7)/3
1000 Dloss=(Qloss)*.022
1010 !
1020 ! AVERAGE SINK TEMPERATURE CALCULATION
1030 Tsink=(T(57)+T(58)+T(59)+T(60))/4
1040 Dtsink=(Dt/T(58))
1050 L=8.0E-3
1060 !
1070 PRINT USING "1X,""CHIP" QNET(W) Tavg-Ts Nu
1080 %UNC IN Nu "",10A"
1090 PRINT
1100 !
1110 !
1120 ! CALCULATION OF NET POWER, Nu, Ra, AND UNCERTAINTIES
1130
1140
1150
1160
1170
1180
1190
1200
1210
1220

```

```

1230 !
1240 FOR J=1 TO 9
1241 PRINTER IS 1
1242 PRINT "J"
1244 PRINT J
1245 PRINTER IS 701
1250 !
1260 ! CALCULATION OF Qnet
1270 Qnet(J)=Power(J)-Qloss
1280 Dqnet=(Dpow(J)^2+Dqloss^2)^.5
1290 !
1300 ! CALCULATION OF Tfilm
1310 Tfilm(J)=(Tavg(J)+Tsink)/2
1320 Dtfilm=(Dtavg^2+Dtsink^2)^.5
1330 !
1340 ! CALCULATION OF A DELTA TEMPERATURE
1350 Delt(J)=Tavg(J)-Tsink
1360 Ddelt=(Dtavg^2+Dtsink^2)^.5
1370 !
1380 ! CALCULATION OF CONVECTION COEFFICIENT
1390 H(J)=Qnet(J)/(Atot*Delt(J))
1400 Dh=H(J)*((Dqnet/Qnet(J))^2+(Ddelt/Delt(J))^2)^.5
1410 !
1420 ! CALCULATION OF CONDUCTION COEFFICIENT
1430 K(J)=(.65-7.89474E-4*Tfilm(J))/10
1440 !
1450 ! CALCULATION OF DENSITY
1460 Rho(J)=(1.825-.00246*Tfilm(J))*1000
1470 !
1480 ! CALCULATION OF SPECIFIC HEAT
1490 Cp(J)=(.241111+3.7037E-4*Tfilm(J))*4180
1500 !
1510 ! CALCULATION OF VISCOSITY
1520 N(J)=1.4074-2.964E-2*Tfilm(J)+3.8018E-4*Tfilm(J)^2-2.7308E-6*Tfilm(J)^3+8.
1530 N(J)=N(J)*1.E-6
1540 !
1550 ! CALCULATION OF BETA
1560 Beta(J)=.00246/(1.825-.00246*Tfilm(J))
1570 !
1580 ! CALCULATION OF ALPHA
1590 Alfa(J)=K(J)/(Rho(J)*Cp(J))
1600 !
1610 ! CALCULATION OF PRANDTL NUMBER AND UNCERTAINTY
1620 Pr(J)=N(J)/Alfa(J)
1630 !
1640 ! CALCULATION OF NUSSELT NUMBER
1650 Nu(J)=H(J)*L/K(J)
1660 Dnu=Nu(J)*(Dh/H(J))
1670 !
1680 ! CALCULATION OF PERCENT UNCERTAINTY IN NUSSELT NUMBER
1690 Pernu=(Dnu/Nu(J))*100
1700 !
1710 ! CALCULATION OF GRASHOF NUMBER AND UNCERTAINTY
1720 Gr(J)=9.81*Beta(J)*(L^3)*Delt(J)/N(J)^2
1730 Dgr=Gr(J)*(Ddelt/Delt(J))
1740 !
1750 ! CALCULATION OF RAYLEIGH NUMBER AND UNCERTAINTY
1760 Ra(J)=Gr(J)*Pr(J)*1.E-6
1770 Dra=Ra(J)*(Dgr/Gr(J))
1780 !

```

```

1794 ! CALCULATION OF FLUX BASED RAYLEIGH NUMBER
1800 !
1810 Raf(J)=/(9.81*Beta(J)+L^4*Qnet(J))/(K(J)*N(J)*Alfa(J)*Atot))*1.E-7
1820 Draf=Raf(J)*(Dqnet/Qnet(J))
1830 !
1840 ! PERCENT UNCERTAINTY IN RAYLEIGH NUMBERS
1850 Perra=(Dra/Ra(J))*100
1860 Perraf=(Draf/Raf(J))*100
1870 !
1880 PRINT USING "1X.D,1X,4(7X.ZZ.DDE,)" ;J,Qnet(J),Delt(J),Nu(J),Pernu
1890 !
1910 PRINT USING "6X,%"TEMPERATURE BASED RAYLEIGH NUMBER * E-6 IS: "",3D.DDE";
Ra(J)
1920 PRINT USING "6X,%"UNCERTAINTY IN THE TEMPERATURE BASED RAYLEIGH NUMBER I
S :"".DDD.DDE":Perra
1930 PRINT USING "6X,%"FLUX BASED RAYLEIGH NUMBER * E-7 IS: "",3D.DDE":Raf(J)
1940 PRINT USING "6X,%"UNCERTAINTY IN FLUX BASED RAYLEIGH NUMBER IS: "",DDD.
DDE":Perraf
1950 PRINT
1960 NEXT J
1970 ASSIGN @File TO *
1980 END

```

3. FastScan

```
19  ! PROGRAM FASTSCAN
20  ! EDITED BY LT. T J BENEDICT
30  !
40  ! THIS PROGRAM SCANS 3 CHANNELS FOR VOLTAGE MEASUREMENTS
50  Ipass=599
60  Pass=0
70  N=0
80  DIM T1(599).V1(2),Y1(599)
90  DIM T2(599).V2(2),Y2(599)
100 DIM T3(599).V3(2),Y3(599)
110 CLEAR 709
120 CLEAR 722
130 !
140 BEEP
150 PRINTER IS 701
160 BEEP
170 INPUT "ENTER THE FIRST FILE NAME: ",Newfile1$
180 INPUT "ENTER THE SECOND FILE NAME: ",Newfile2$
190 INPUT "ENTER THE THIRD FILE NAME: ",Newfile3$
200 INPUT "ENTER THE VOLTMETER READING: ".VS
210 PRINT USING "15X,."THESE RESULTS ARE NOW STORED ON DISK 'FASTSCAN' .",10A"
220 PRINT
230 PRINT USING "25X,."FILE: .",10A";Newfile1$
240 PRINT
250 PRINT USING "25X,."FILE: .",10A";Newfile2$
260 PRINT
270 PRINT USING "25X,."FILE: .",10A";Newfile3$
280 PRINT
290 WAIT 1
300 BEEP
310 OUTPUT 709;"AE1"
320 WAIT 2
330 BEEP
340 OUTPUT 722;"T4 F1 R1 P0 Z0 1STI S01 1STN"
350 !
360 ! LOOP NUMBER ONE
370 !
380 OUTPUT 709;"AF0 AL0"
390 OUTPUT 709;"AS"
400 BEEP
410 Timedate1=TIMEDATE
420 FOR Jj=0 TO Ipass
430 OUTPUT 722;"T3"
440 ENTER 722;V1(*)
450 T1(Pass)=V1(1)
460 Pass=Pass+1
470 N=N+1
480 NEXT Jj
490 Timedate2=TIMEDATE
500 Totaltime1=Timedate2-Timedate1
510 OUTPUT 722;"AC0"
520 Pass=0
530 !
540 ! LOOP NUMBER TWO
550 !
560 OUTPUT 709;"AF12 AL12"
570 OUTPUT 709;"AS"
580 BEEP
```

```

272 BEEP
274 FOR J1=0 TO Ipass
275 OUTPUT 722;"T3"
276 ENTER 722;V2(*)
277 T2(Pass)=V2(1)
278 Pass=Pass+1
279 NEXT Jj
280 OUTPUT 722;"AC12"
281 Pass=0
282 !
283 ! LOOP NUMBER THREE
284 !
285 OUTPUT 709;"AF31 AL31"
286 OUTPUT 709;"AS"
287 BEEP
288 BEEP
289 BEEP
291 FOR J1=0 TO Ipass
292 OUTPUT 722;"T3"
293 ENTER 722;V3(*)
294 T3(Pass)=V3(1)
295 Pass=Pass+1
296 NEXT Jj
297 !
298 ! END LOOPS
299 !
300 PRINT USING "15X,;"THE TOTAL TIME ELAPSED WAS (SECONDS):",,2X,(DDD.DDE)":;
totaltime1
301 PRINT
302 PRINT USING "15X,;"THE TOTAL NUMBER OF SCANS WAS : ",,2X,(DDDD.D.2X)":N
303 PRINT
304 PRINT USING "15X,;"THE VOLTMETER READING WAS: ",,10A,;"VS
306 PRINTER IS 1
307 BEEP
308 !
309 ! TRANSFER FIRST SCAN DATA
310 !
311 CREATE BDAT Newfile1$,20
312 ASSIGN @File TO Newfile1$
313 OUTPUT @File;T1(*)
314 FOR I1=0 TO Ipass
320 T1(I1)=.10086091+25727.9*T1(I1)-767345.8*T1(I1)^2+78002556*T1(I1)^3
340 NEXT I1
341 !
342 ! TRANSFER SECOND SCAN DATA
343 !
344 CREATE BDAT Newfile2$,20
345 ASSIGN @File TO Newfile2$
346 OUTPUT @File;T2(*)
347 FOR I1=0 TO Ipass
348 T2(I1)=.10086091+25727.9*T2(I1)-767345.8*T2(I1)^2+78002556*T2(I1)^3
349 NEXT I1
350 !
351 ! TRANSFER THIRD SCAN DATA
352 !
353 CREATE BDAT Newfile3$,20
354 ASSIGN @File TO Newfile3$
355 OUTPUT @File;T3(*)
356 FOR I1=0 TO Ipass
357 T3(I1)=.10086091+25727.9*T3(I1)-767345.8*T3(I1)^2+78002556*T3(I1)^3
358 NEXT I1
390 STOP
400 END

```

4. Plot

```
10  | FILE NAME: PLOT
20  | EDITED BY Lt T J BENEDICT
30  |
40  |
50  | THIS PROGRAM PLOTS THE DATA ACQUIRED BY
60  | PROGRAM "FASTSCAN".
70  |
80  | PRINTER IS 705
90  | BEEP
100 | Xmin=0
110 | Xmax=200
120 | BEEP
130 | INPUT "ENTER MINIMUM AND MAXIMUM Y-VALUES",Ymin,Ymax
140 | BEEP
150 | Xstep=.20
160 | BEEP
170 | Ystep=.2
180 | BEEP
190 | PRINT "IN:SP1;IP 2000.2000.8000,7000;""
200 | PRINT "SC 0.100,0.100;TL 2,0;""
210 | Sfx=100/(Xmax-Xmin)
220 | Sfy=100/(Ymax-Ymin)
230 | PRINT "PU 0.0 PD"
240 | FOR Xa=Xmin TO Xmax STEP Xstep
250 | X=(Xa-Xmin)*Sfx
260 | PRINT "PA";X,";0; XT;""
270 | NEXT Xa
280 | PRINT "PA 100.0:PU;""
290 | PRINT "PU PA 0.0 PD"
300 | FOR Ya=Ymin TO Ymax STEP Ystep
310 | Y=(Ya-Ymin)*Sfy
320 | PRINT "PA 0.,";Y,"YT"
330 | NEXT Ya
340 | PRINT "PA 0,100 TL 0 2"
350 | FOR Xa=Xmin TO Xmax STEP Xstep
360 | X=(Xa-Xmin)*Sfx
370 | PRINT "PA";X,";100; XT"
380 | NEXT Xa
390 | PRINT "PA 100,100 PU PA 100,0 PD"
400 | FOR Ya=Ymin TO Ymax STEP Ystep
410 | Y=(Ya-Ymin)*Sfy
420 | PRINT "PD PA 100.,";Y,"YT"
430 | NEXT Ya
440 | PRINT "PA 100,100 PU"
450 | PRINT "PA 0,-2 SR 1.5,2"
460 | FOR Xa=Xmin TO Xmax STEP Xstep
470 | X=(Xa-Xmin)*Sfx
480 | PRINT "PA";X,";0; "
490 | PRINT "CP -2,-1;LB";Xa; ""
500 | NEXT Xa
510 | PRINT "PU PA 0,0"
520 | FOR Ya=Ymin TO Ymax STEP Ystep
530 | IF ABS(Ya)<1.E-5 THEN Ya=0
540 | Y=(Ya-Ymin)*Sfy
550 | PRINT "PA 0.,";Y,""
560 | PRINT "CP -5.-.25;LB";Ya; ""
570 | NEXT Ya
580 | BEEP
590 | Idl=0
600 | IF Idl=0 THEN
```

```

610 BEEP
620 Xlabel$="Time (sec)"
630 BEEP
640 Ylabel$="Temperature (C)"
650 PRINT "SR 1.5.2;PU PA 50,-10 CP";-LEN(Xlabel$)/2;"0;LB";Xlabel$;;
660 PRINT "PA -11.50 CP 0.,";-LEN(Ylabel$)/2*5/6;"DI 0.1;LB";Ylabel$;;
670 END IF
680 PRINT "CP 0.0"
690 BEEP
700 INPUT "ENTER THE NAME OF THE DATA FILE",D_file$
710 ASSIGN @File TO D_file$
720 BEEP
730 Md=0
740 BEEP
750 Npairs=600
760 BEEP
770 PRINTER IS 1
780 Sym=1
790 PRINTER IS 705
800 PRINT "PU DI"
810 IF Sym=1 THEN PRINT "SM."
820 IF Sym=2 THEN PRINT "SM+"
830 IF Sym=3 THEN PRINT "SMo"
840 IF Md>1 THEN
850 FOR I=1 TO (Md-1)
860 ENTER @File;Xa,Ya
870 NEXT I
880 END IF
890 FOR Xa=0 TO 199 STEP .3333333
900 ENTER @File;Ya
910 Ya=.10086091+25727.9*Ya-767345.8*Ya^2+78002556*Ya^3
920 X=(Xa-Xmin)*Sfx
930 Y=(Ya-Ymin)*Sfy
940 IF Sym>3 THEN PRINT "SM"
950 IF Sym<4 THEN PRINT "SR 1.4,2.4"
960 PRINT "PA",X,Y,"PD"
970 IF Sym>3 THEN PRINT "SR 1.2,1.6"
980 IF Sym=4 THEN PRINT "UC2,4,99,0,-8,-4,0,0,8,4,0,;"
990 IF Sym=5 THEN PRINT "UC3,0,99,-3,-6,-3,6,3,6,3,-6,;"
1000 IF Sym=6 THEN PRINT "UC0,5,3,99,3,-8,-6,0,3,8,;"
1010 IF Sym=7 THEN PRINT "UC0,-5,3,99,-3,8,6,0,-3,-8,;"
1020 NEXT Xa
1021 PRINT "PU"
1030 BEEP
1040 ASSIGN @File TO *
1050 END

```

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